



HEUFT *eXaminer II* XAC



HEUFT *eXaminer II* XOS



HEUFT *eXaminer II* XB

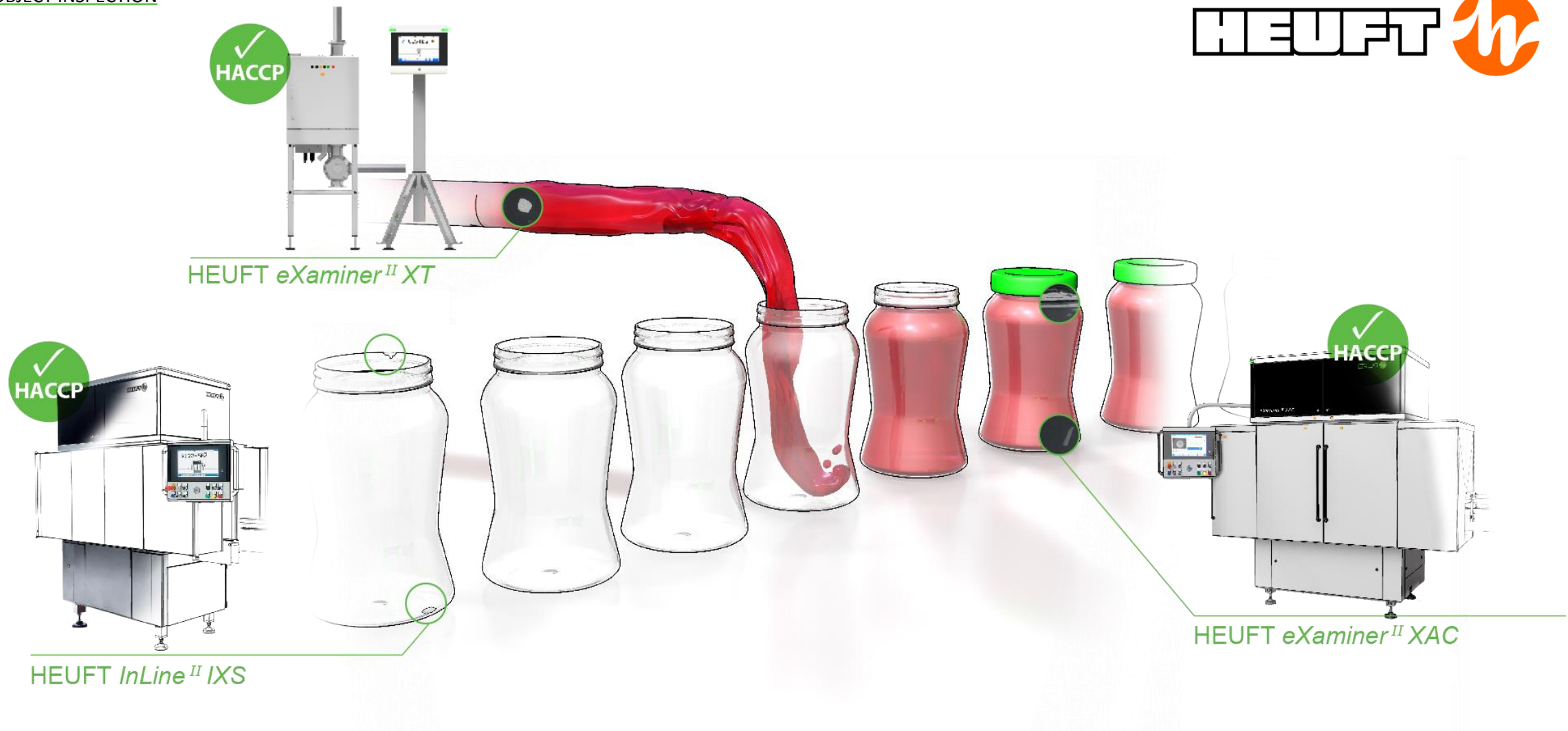


HEUFT *eXaminer II* XT

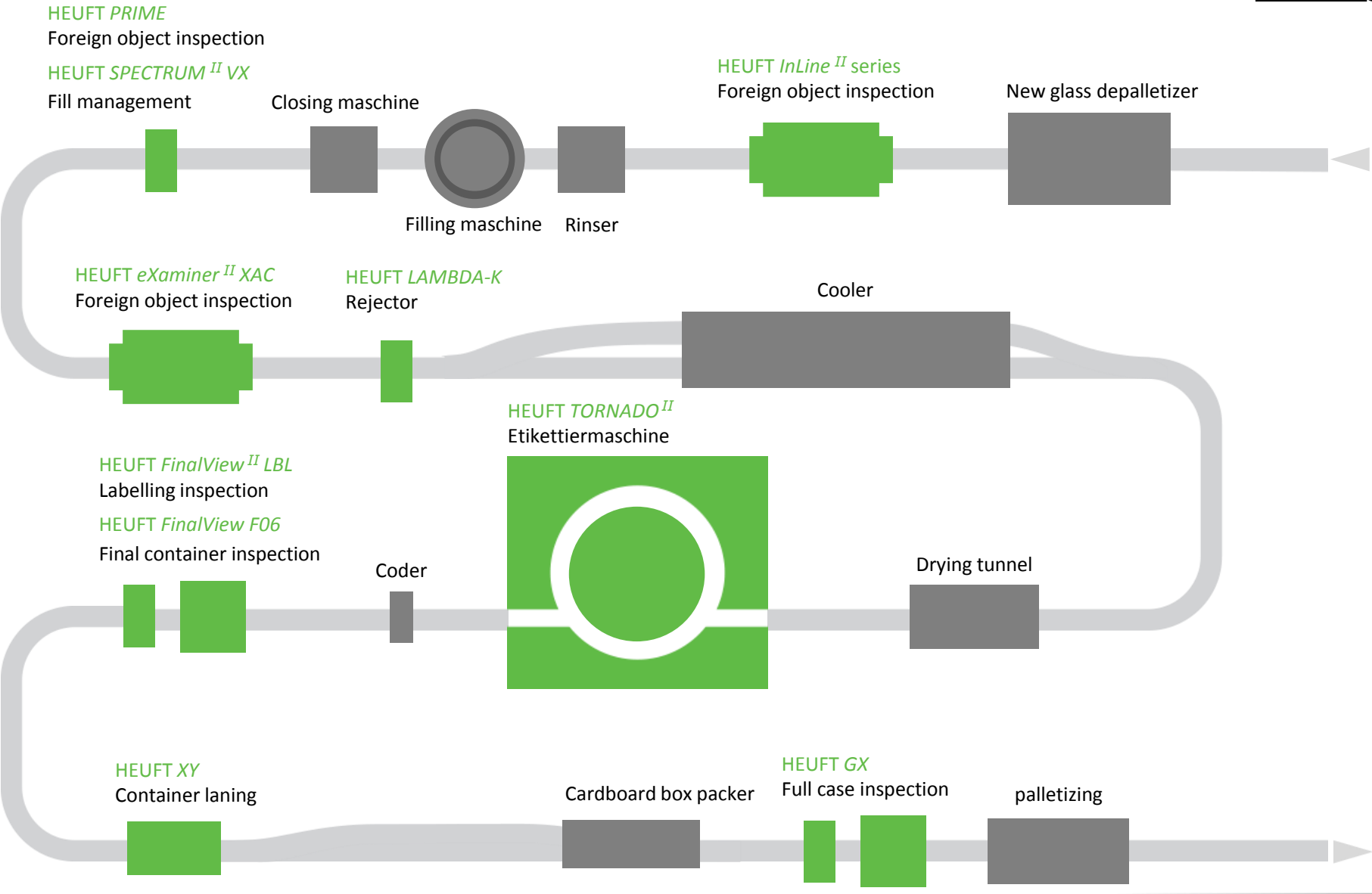


HEUFT *eXaminer II* XS

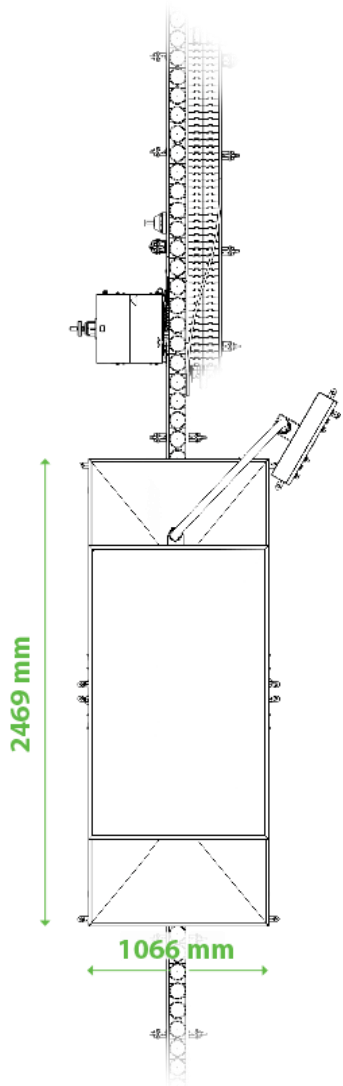




Safe along the complete line!



FOREIGN OBJECT INSPECTION



 **up to**
1,200
containers per minute



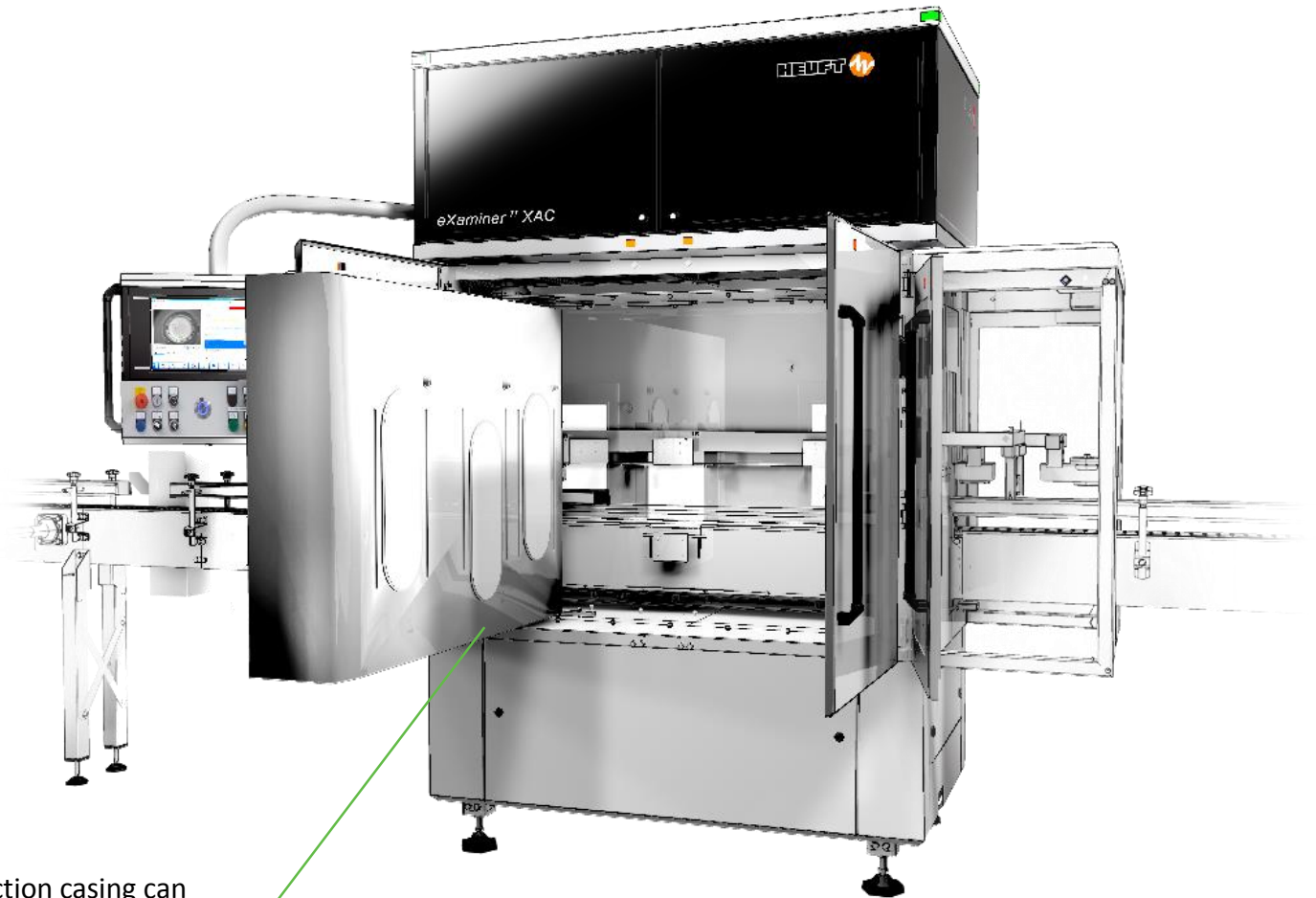
HEUFT rejector
High-speed rejection system

HEUFT conveyor
Powerful conveyors

HEUFT synchron
Conveyor control system

Turnkey-solution

Easy Access

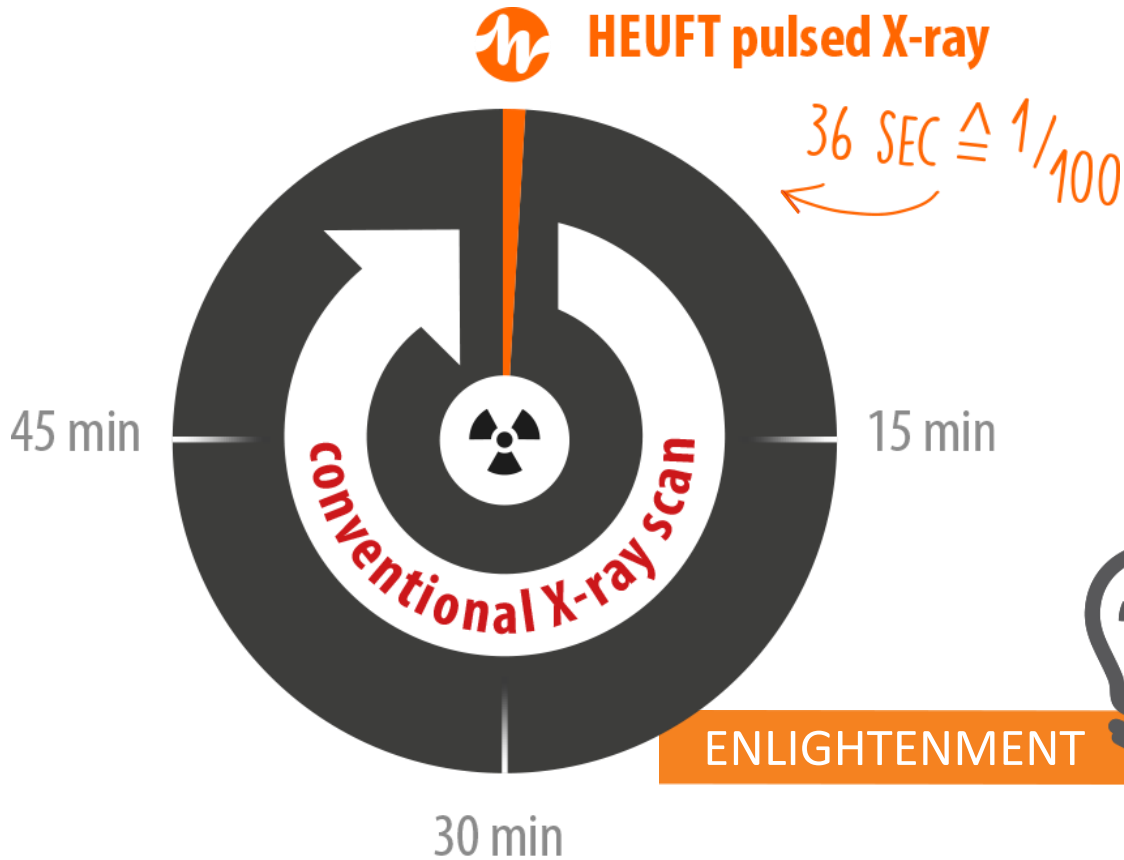


Inspection casing can
be folded open





HEUFT *CleanDesign*



ONLY AVAILABLE WITH THE
HEUFT *eXaminer^{II}* TECHNOLOGY

Pulsed X-ray technology

**MAXIMUM PRECISION AND
MINIMUM RADIATION!**

Pulsed X-ray technology

Ball floats on the surface

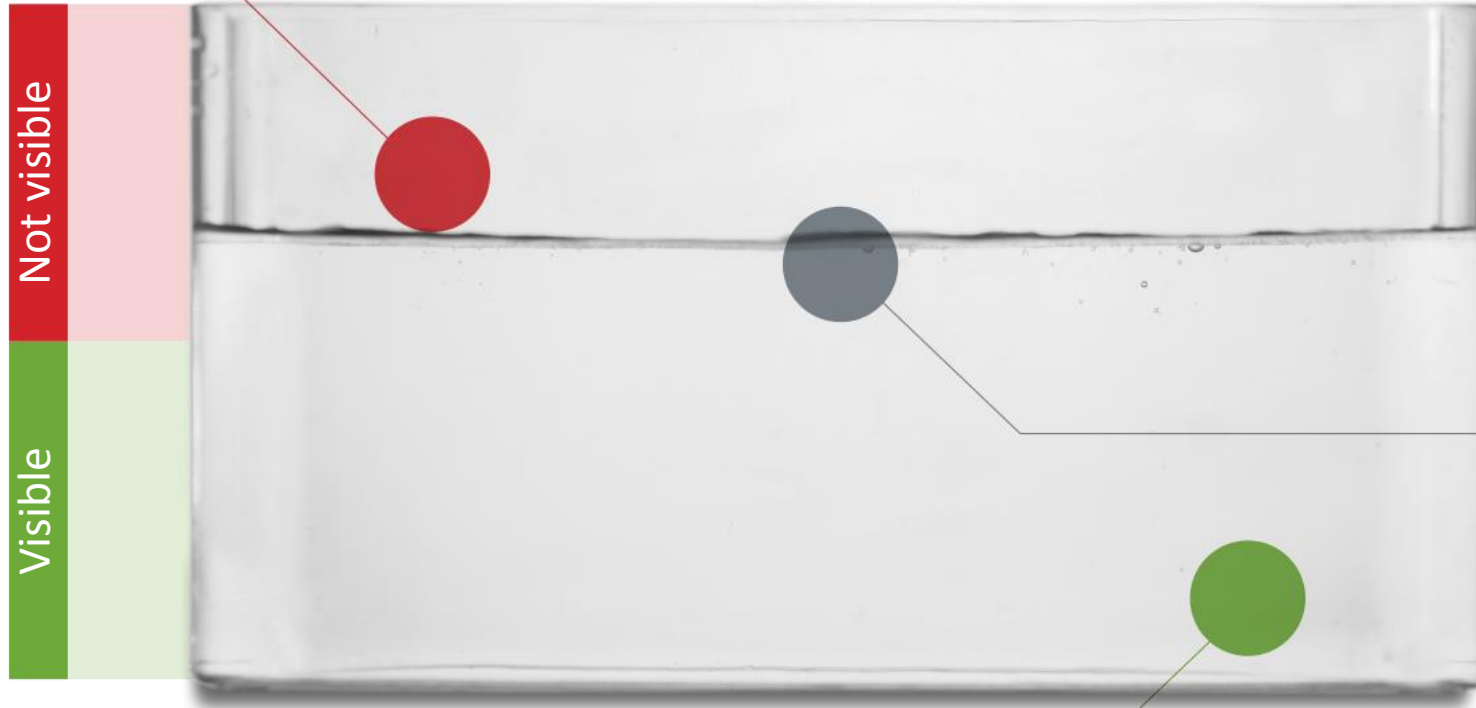
- density $0.08 \text{ [g/cm}^3\text{]}$
- e.g. polystyrene



Not visible



Visible



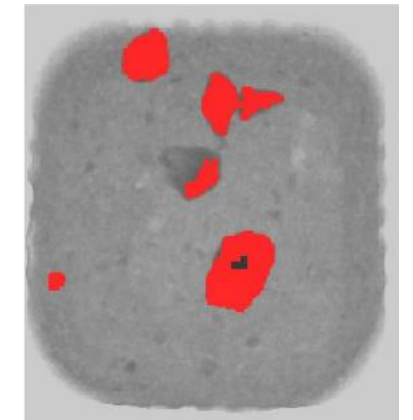
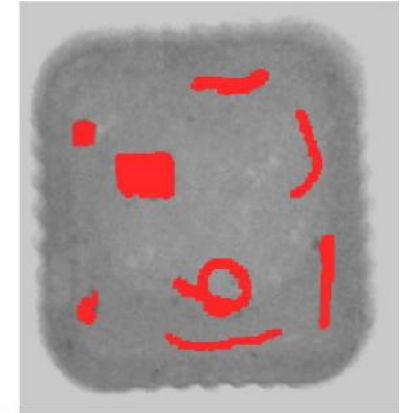
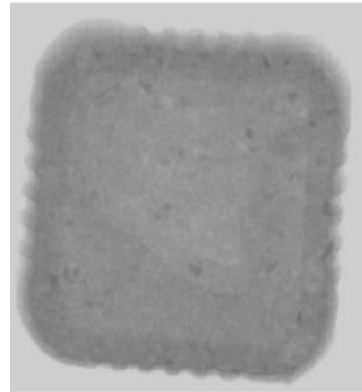
Ball sinks halfway

- density $0.5 \text{ [g/cm}^3\text{]}$
- e.g. wood

Ball sinks to the bottom

- density $7.93 \text{ [g/cm}^3\text{]}$
- e.g. steel

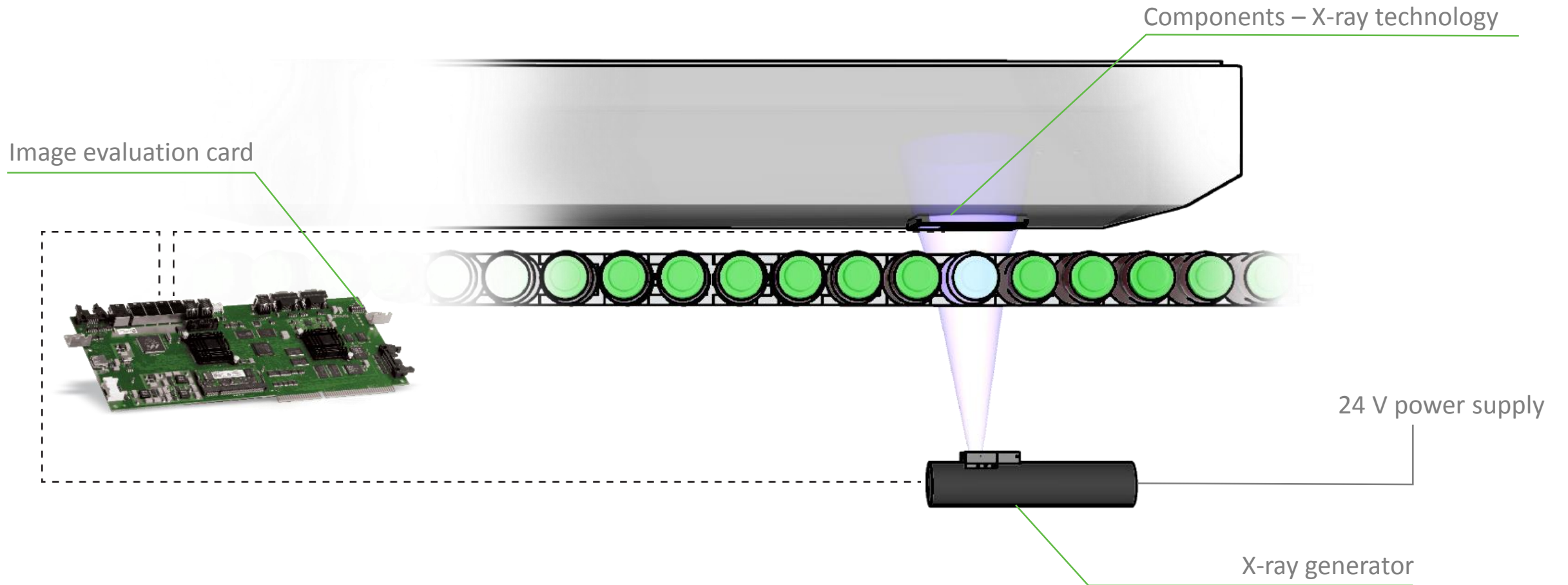
The invisible? Visible!



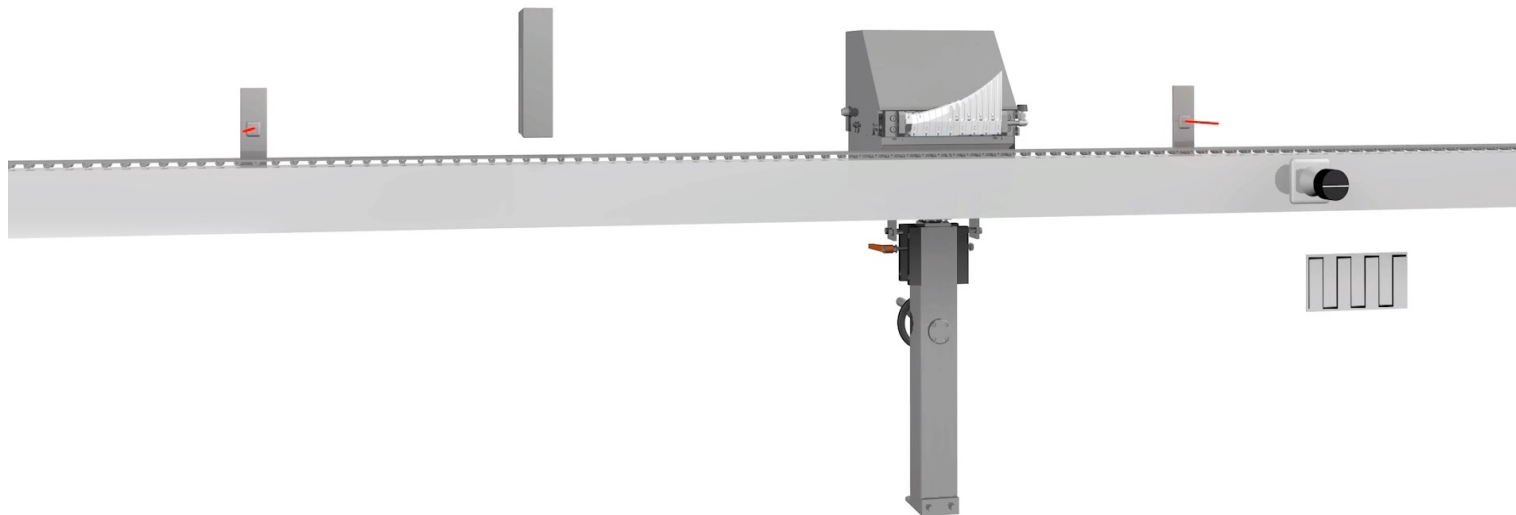
Physical limit



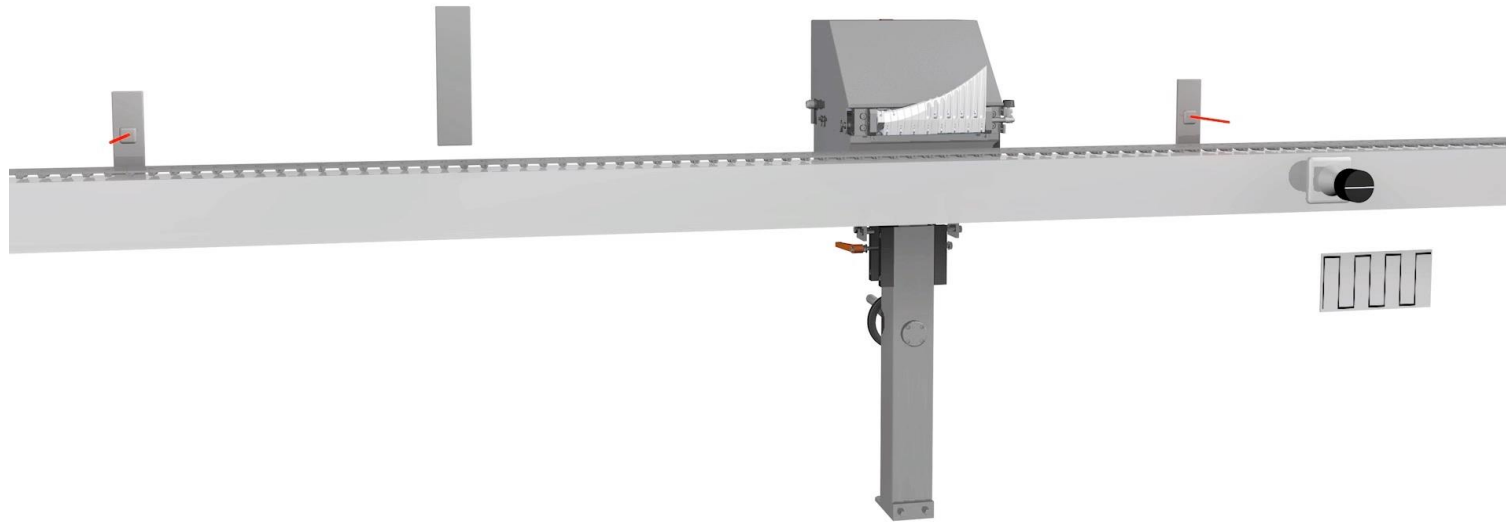
Influences – detection performance



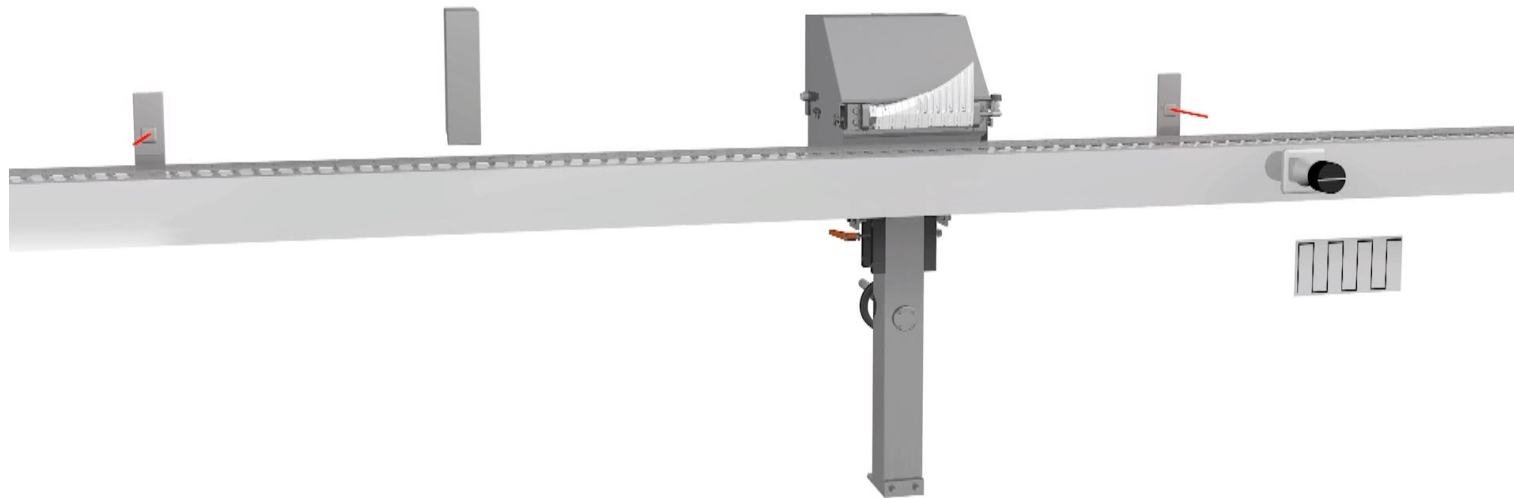
Digital X-ray image receiver



SHIFTING REGISTER AND REJECT VERIFICATION 1



SHIFTING REGISTER AND REJECT VERIFICATION 2

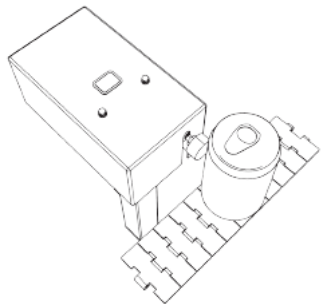


SHIFTING REGISTER AND REJECT VERIFICATION 3

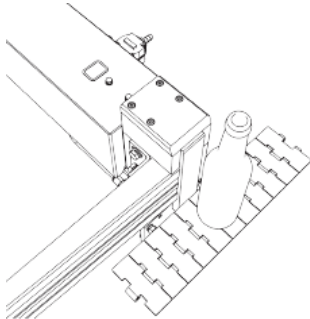
Additional equipment
from the beginning
to the end



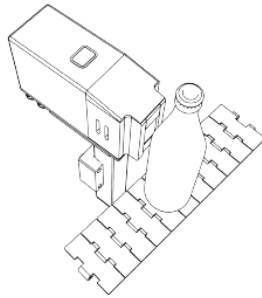
HEUFT *pusher*
Compact discharger



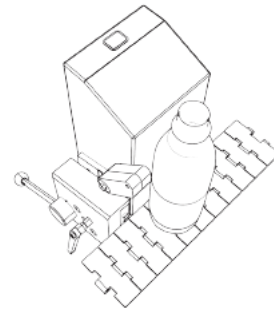
HEUFT *mono*
Careful rejector



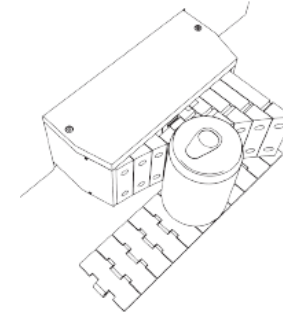
HEUFT *e-mono*
High-speed rejector
without compressed air



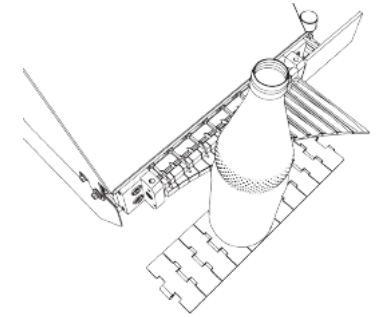
HEUFT *flip*
Smooth rejection



HEUFT *DELTA-FW*
Dynamic rejection curve



HEUFT *DELTA-K*
Gentle folding rejector

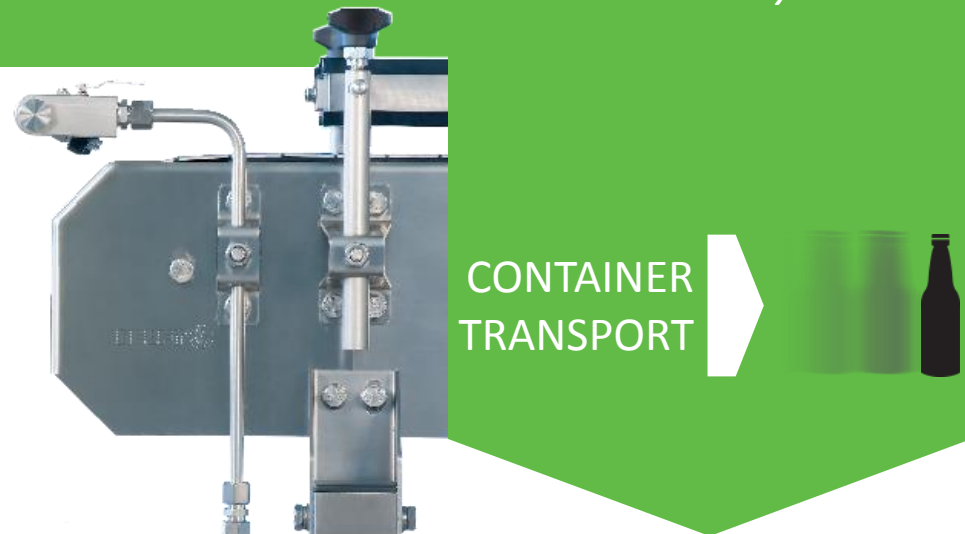




HEUFT *conveyor*

HEUFT *beetec*

HEUFT *synchron TXI*



HEUFT *PROFILER* -family

Production data acquisition (PDA) and
line analysis in real time



HEUFT *STRATEGY II* -Server



Extension

HEUFT *PROFILER advanced*

HEUFT *PROFILER*

Upgrade

HEUFT *PROFILER elemental*



Full container inspection with pulsed X-ray technology based on the HEUFT *SPECTRUM II*.

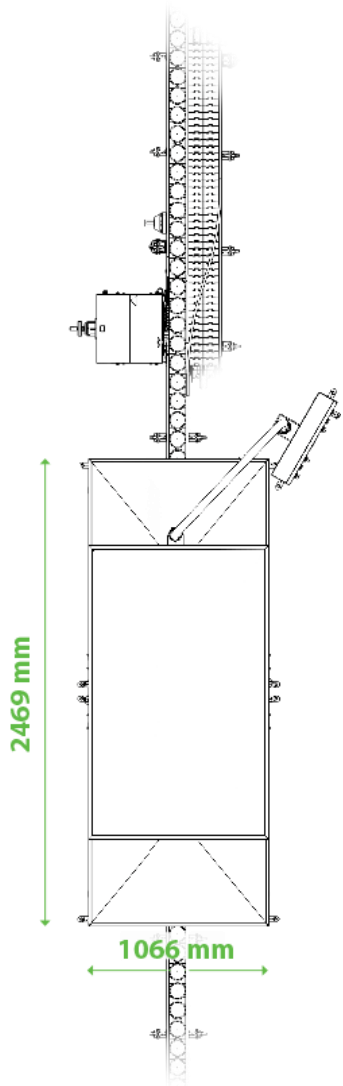
HEUFT *eXaminer II* XAC



Full container inspection with pulsed X-ray technology based on the HEUFT *SPECTRUM II*.



FOREIGN OBJECT INSPECTION



 **up to**
1,200
containers per minute



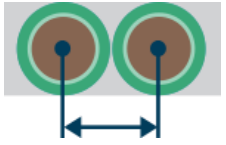
HEUFT rejector
High-speed rejection system

HEUFT conveyor
Powerful conveyors

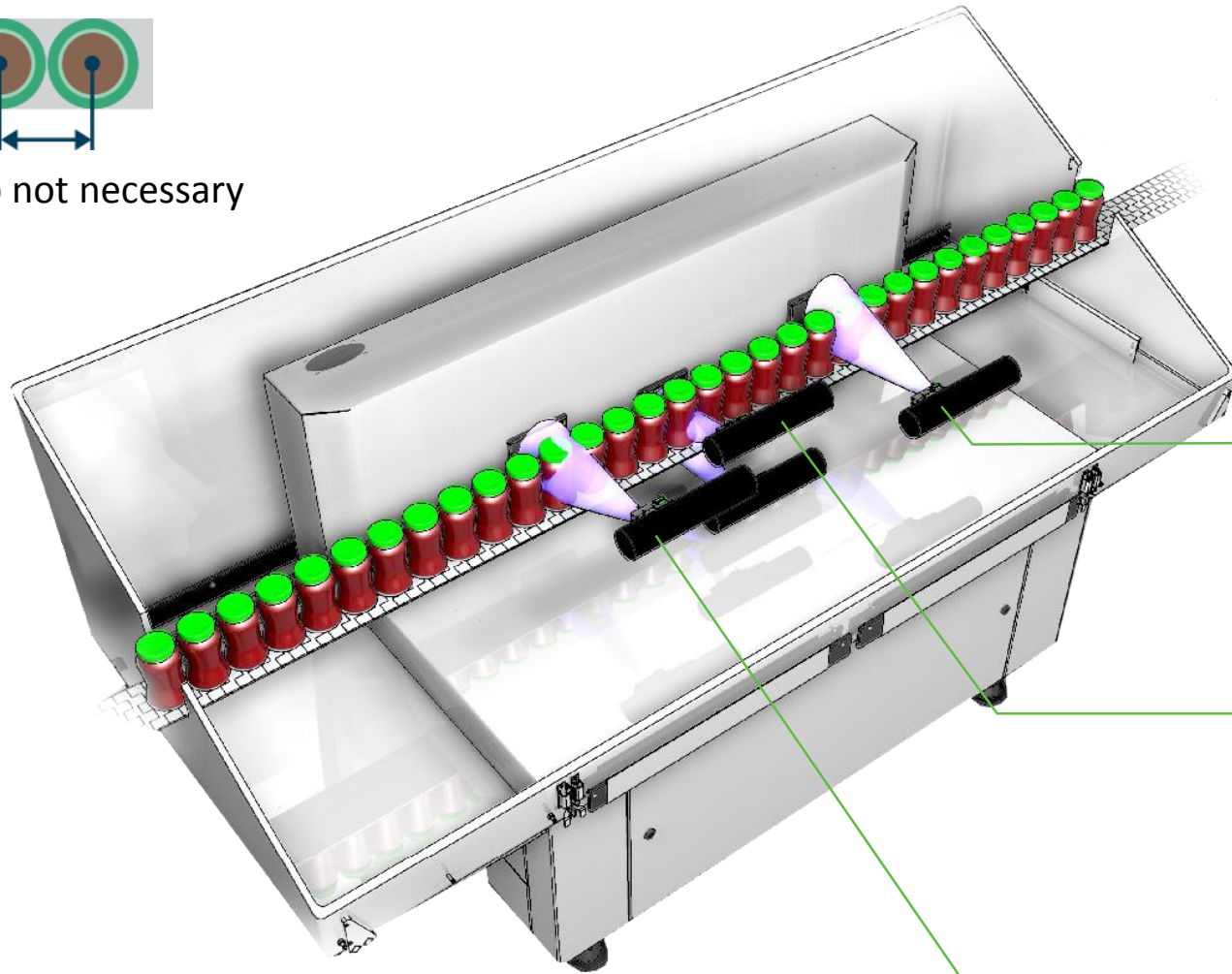
HEUFT synchron
Conveyor control system

Turnkey-solution

FOREIGN OBJECT INSPECTION



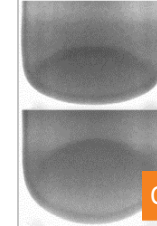
Gap not necessary



Sidewall 1

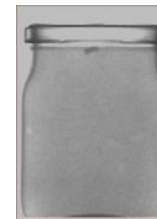


Double base inspection



Only available from HEUFT

Sidewall 2

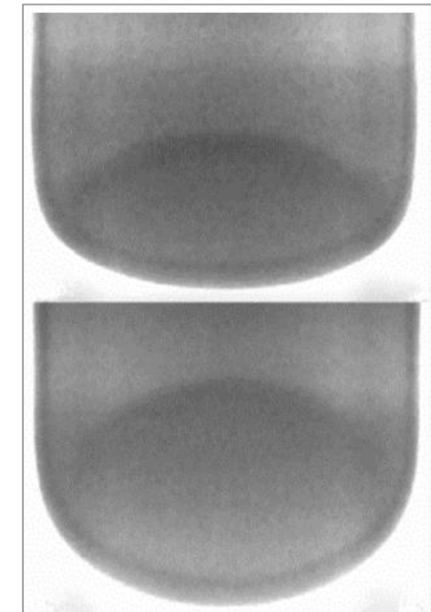
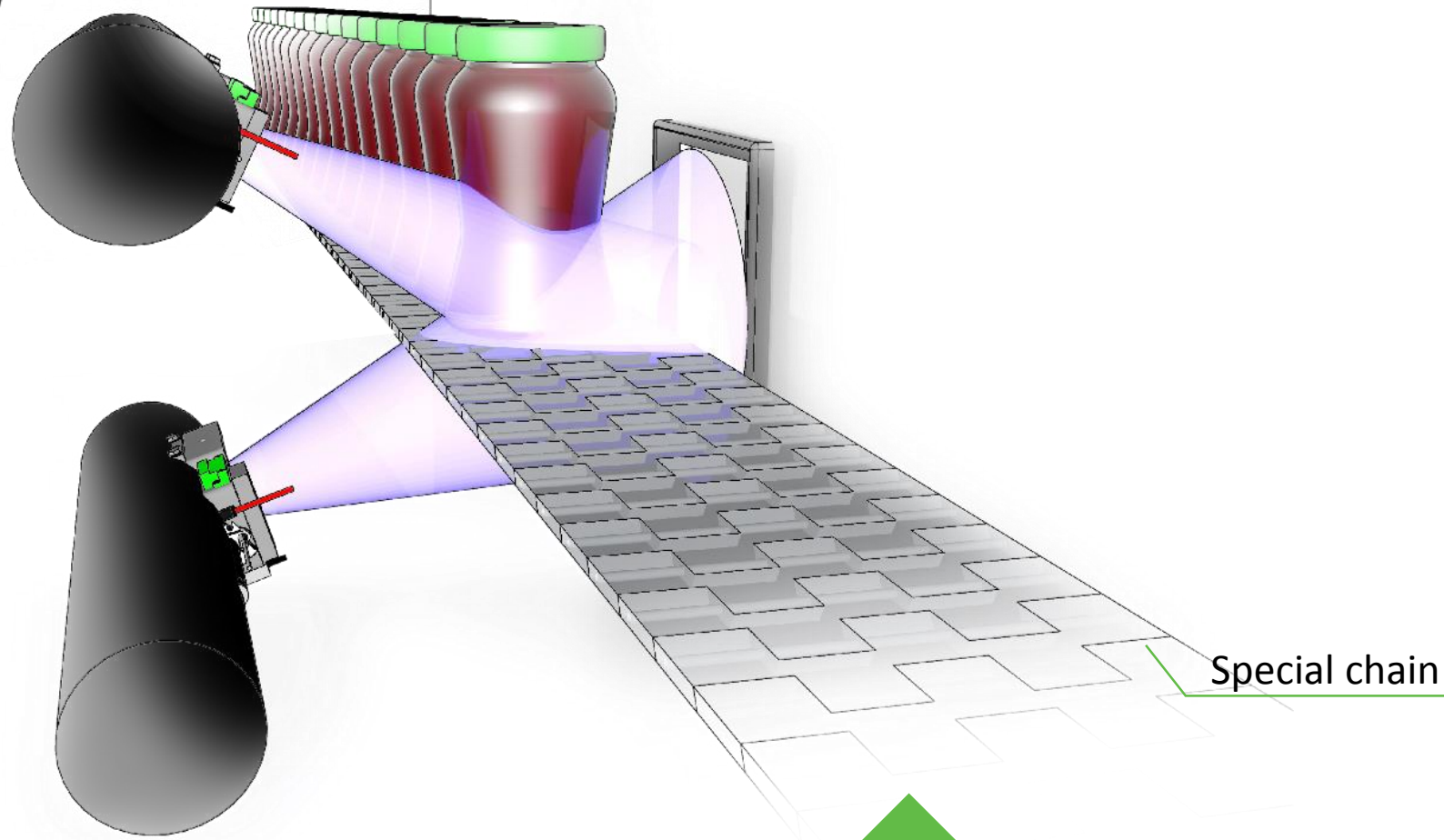


HEUFT *eXaminer II* XAC: the detection modules

FOREIGN OBJECT INSPECTION

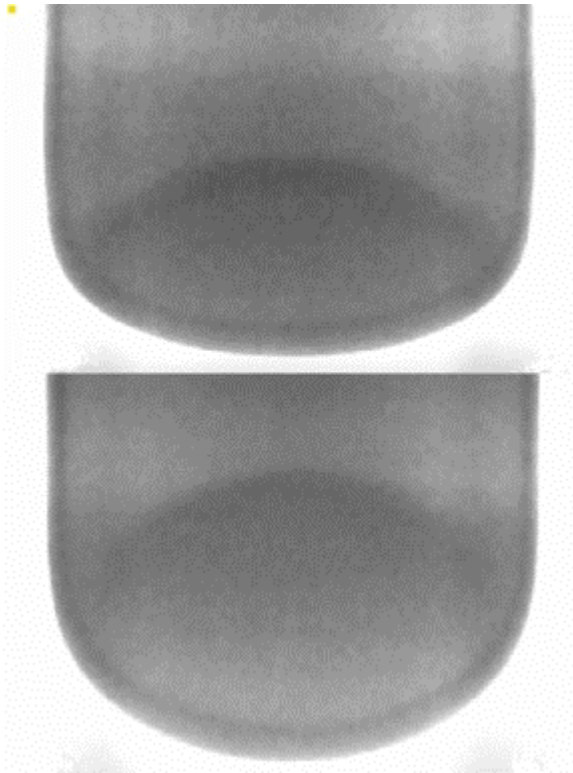


Only available from HEUFT

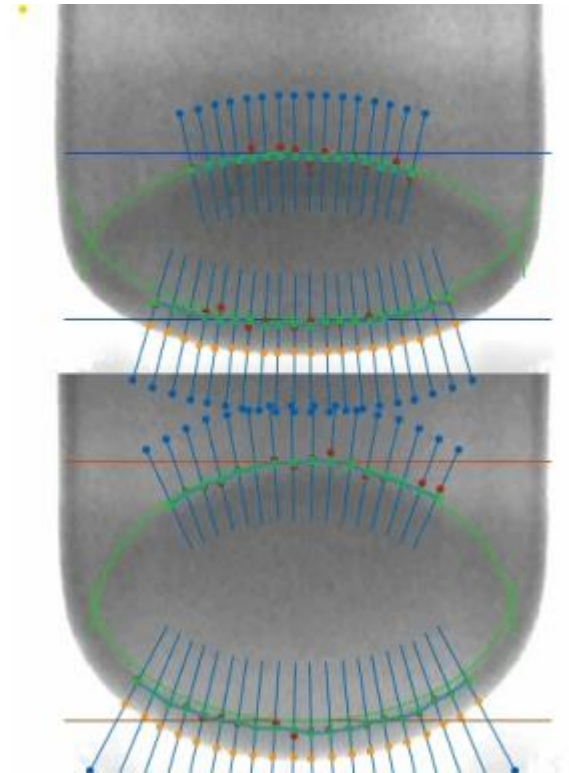


Glass

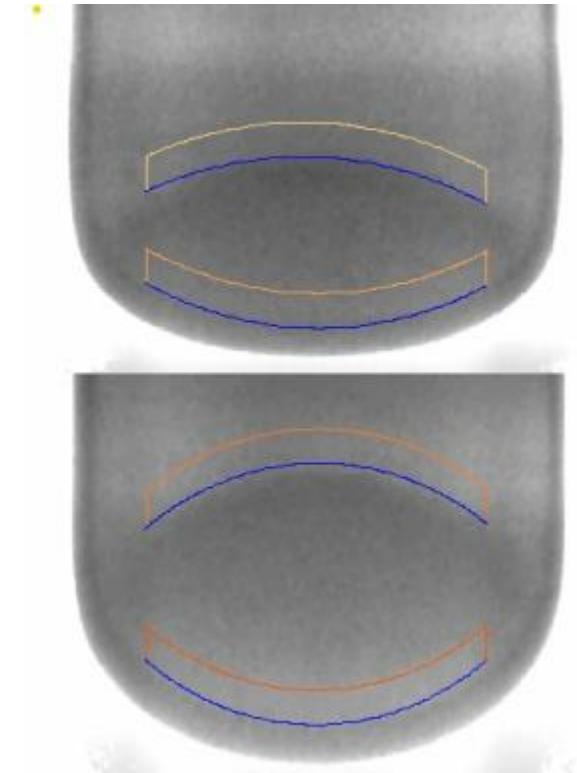
HEUFT *eXaminer II* XAC: double base inspection



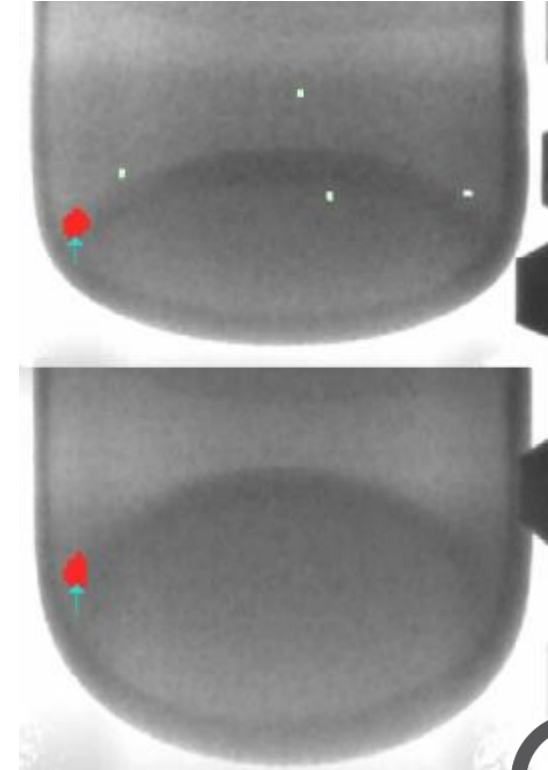
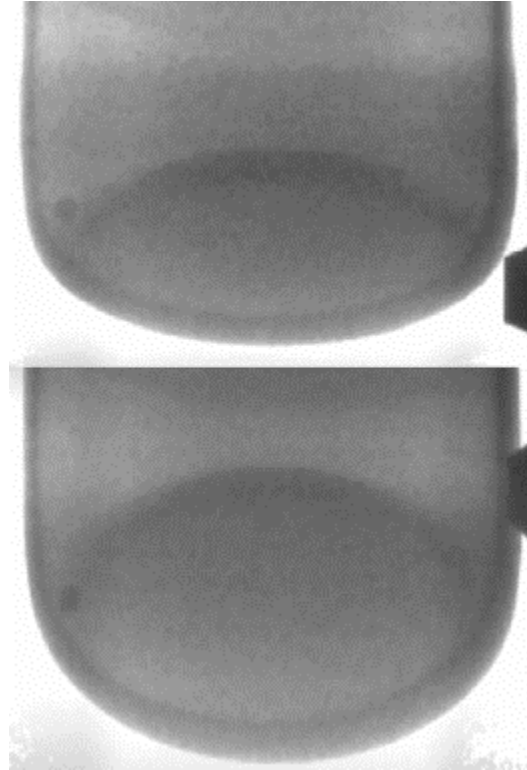
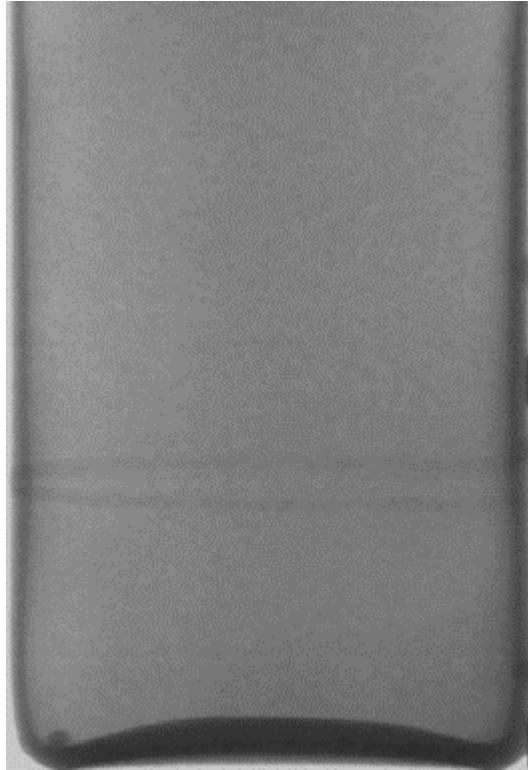
Base mask



Dynamic glass
thickness measurement



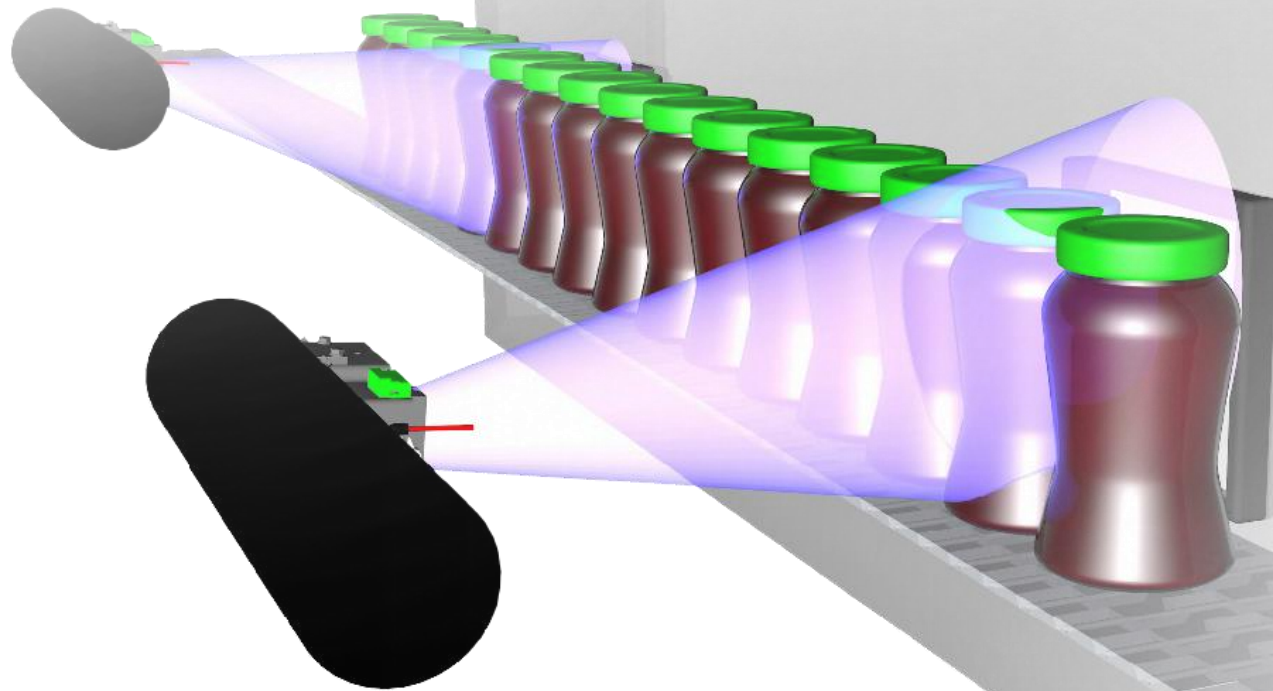
Inspection in
all areas



ENLIGHTENMENT



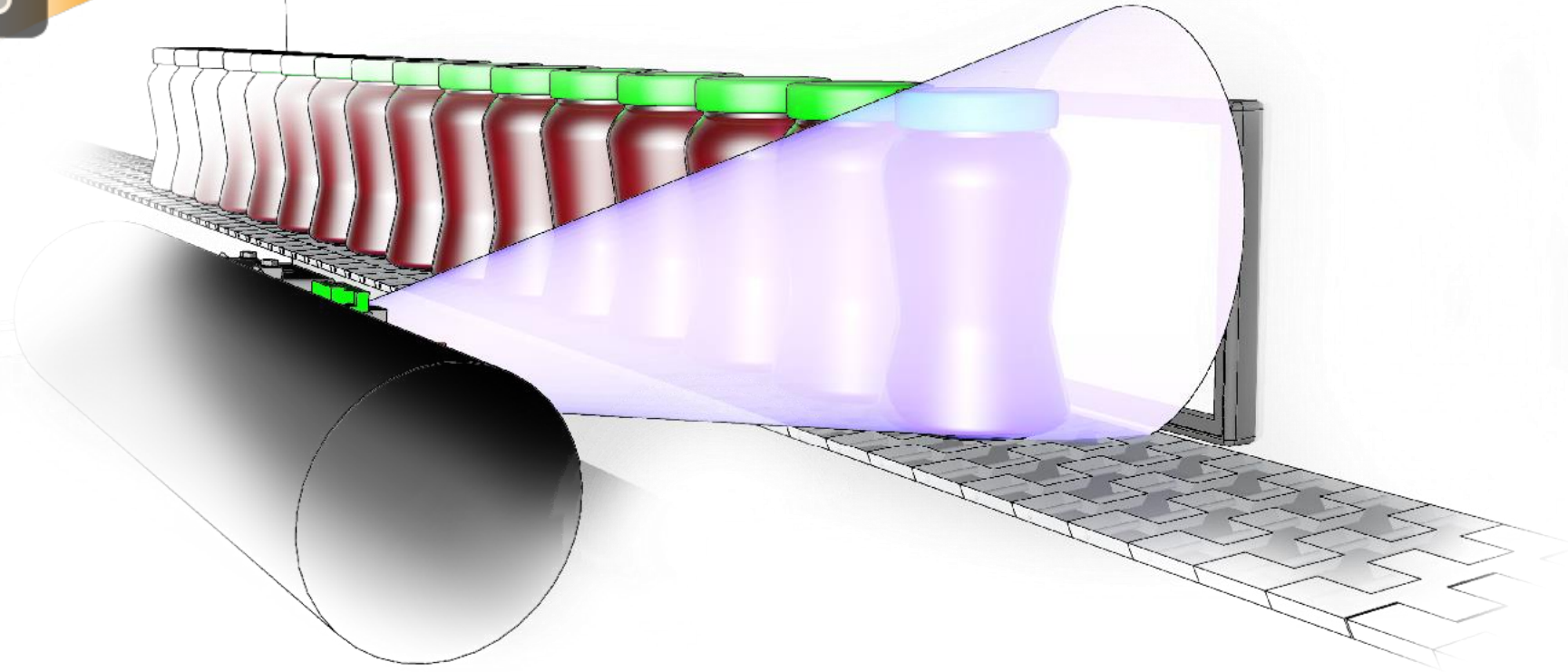
Enlightenment – base inspection



HEUFT *eXaminer^{II}* XAC: sidewall modules

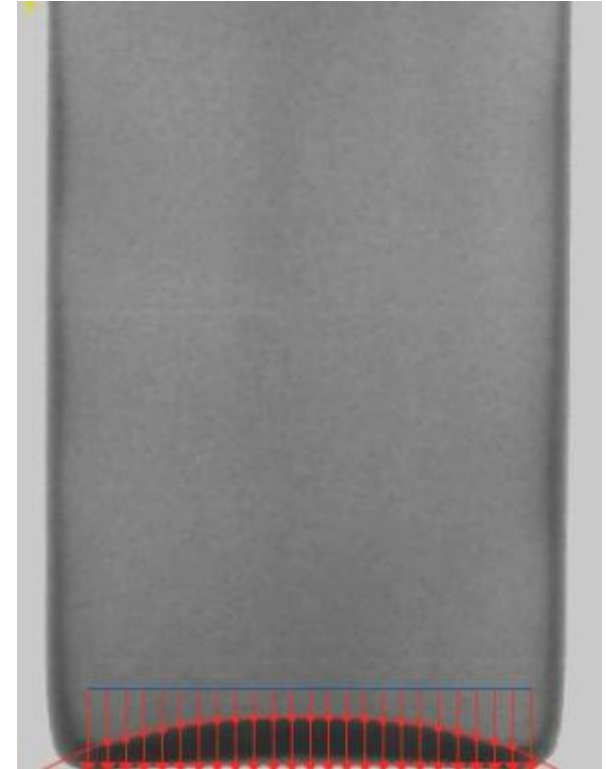
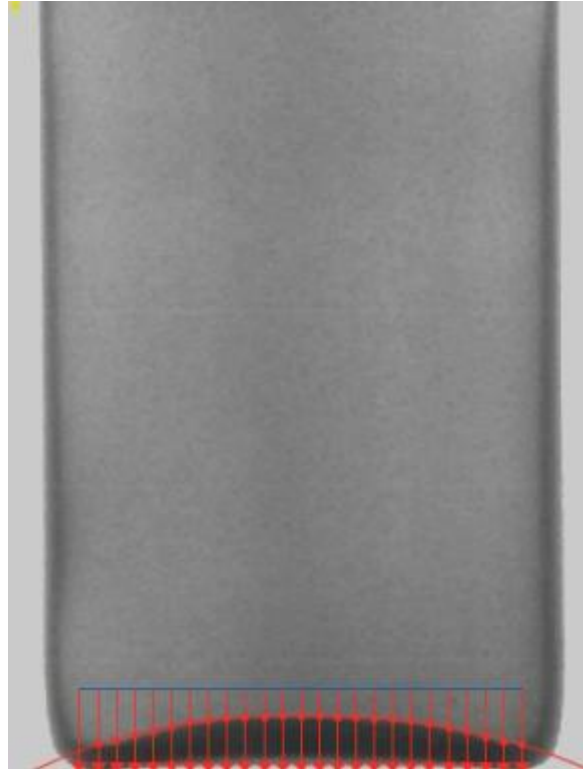
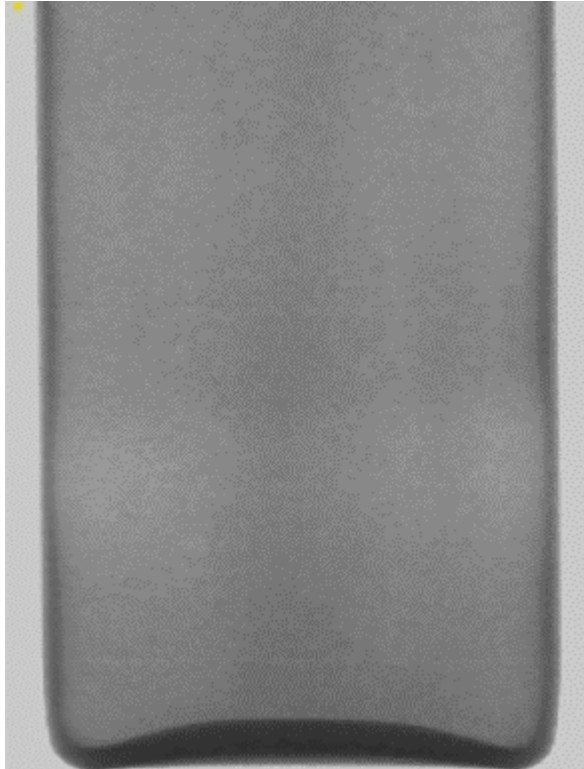
DOUBLE SIDEWALL INSPECTION

Sidewall 1



Glass

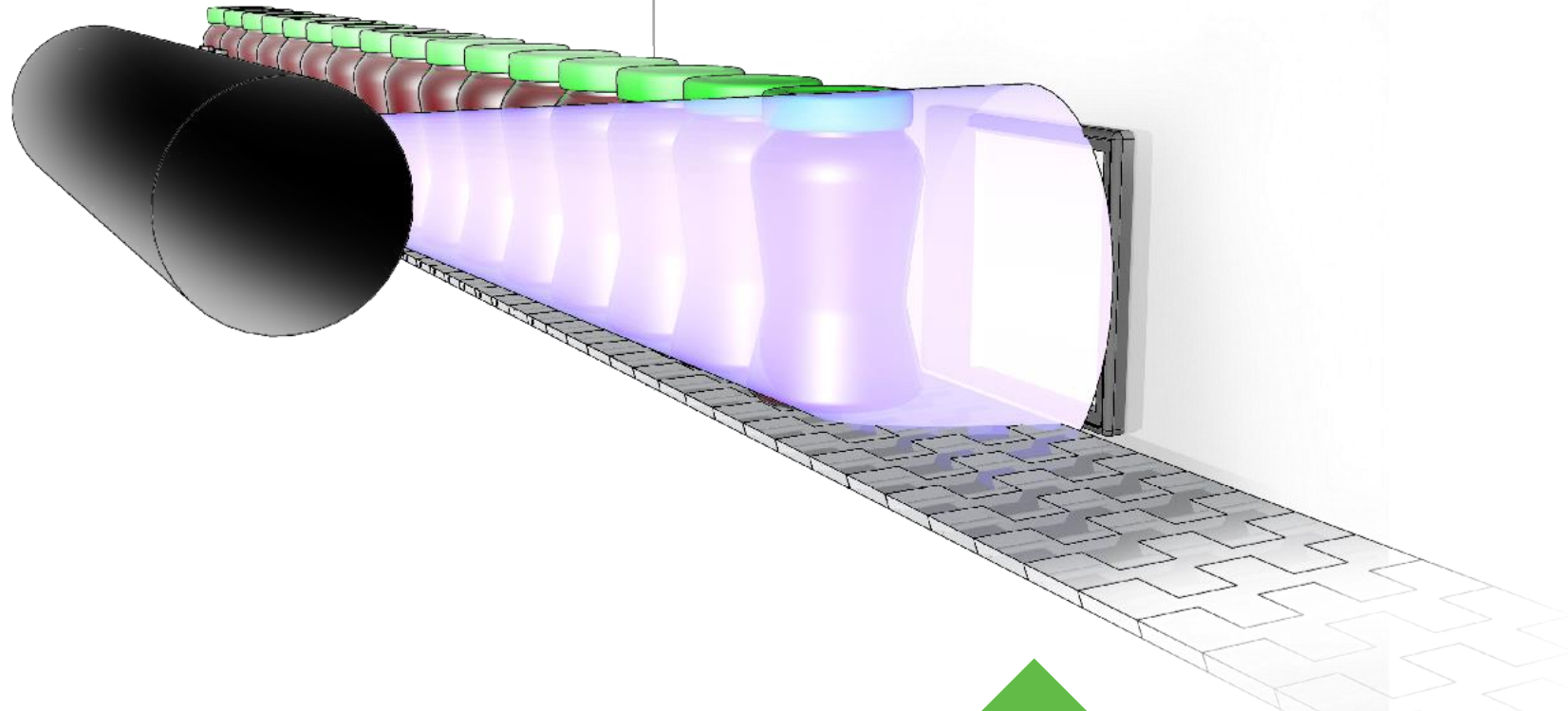
HEUFT *eXaminer^{II}* XAC: sidewall module 1



Video for sidewall module 1

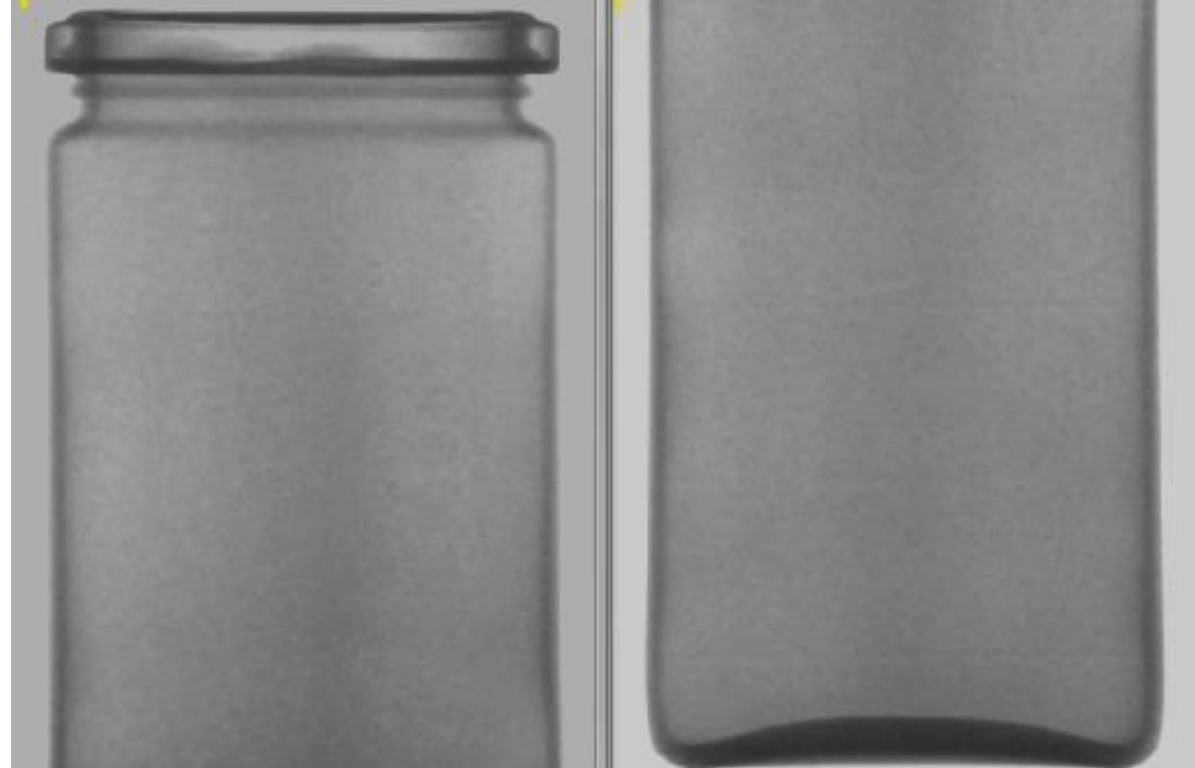
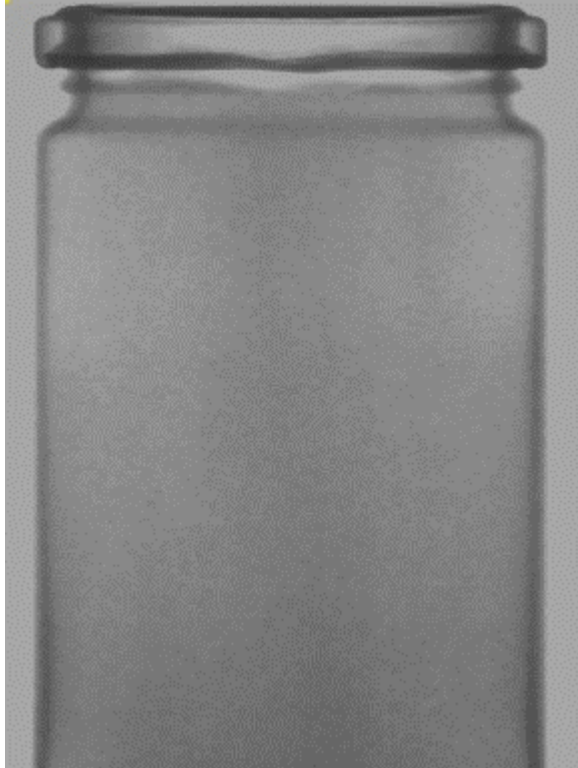
DOUBLE SIDEWALL INSPECTION

Sidewall 2

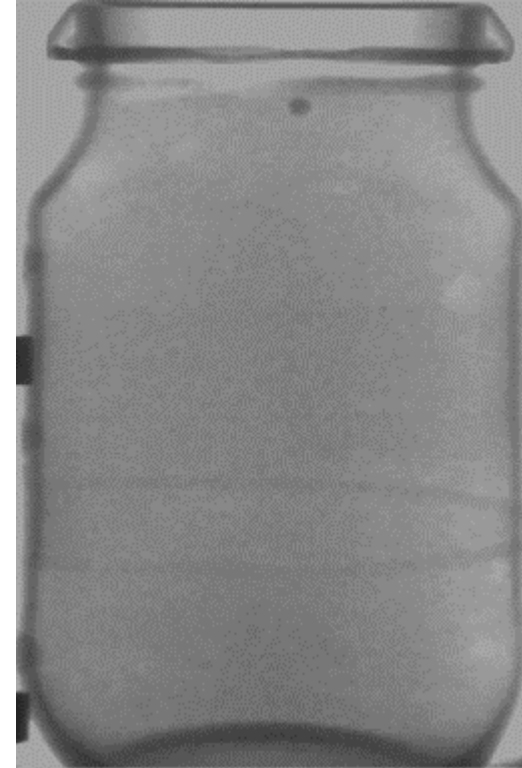
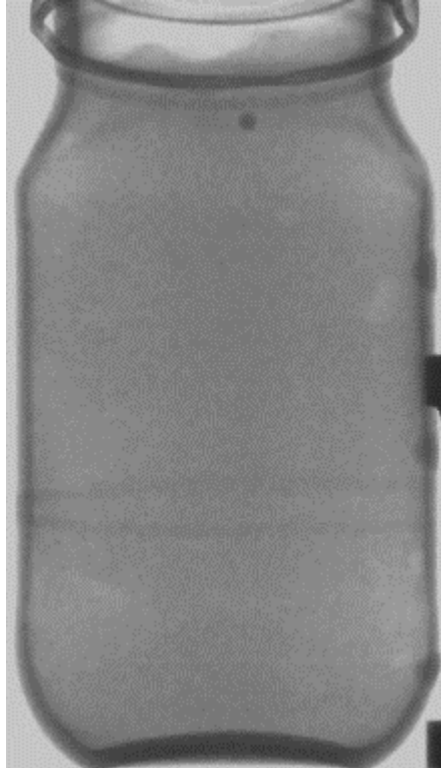


Glass

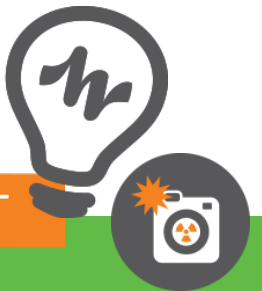
HEUFT *eXaminer II* XAC: sidewall module 2



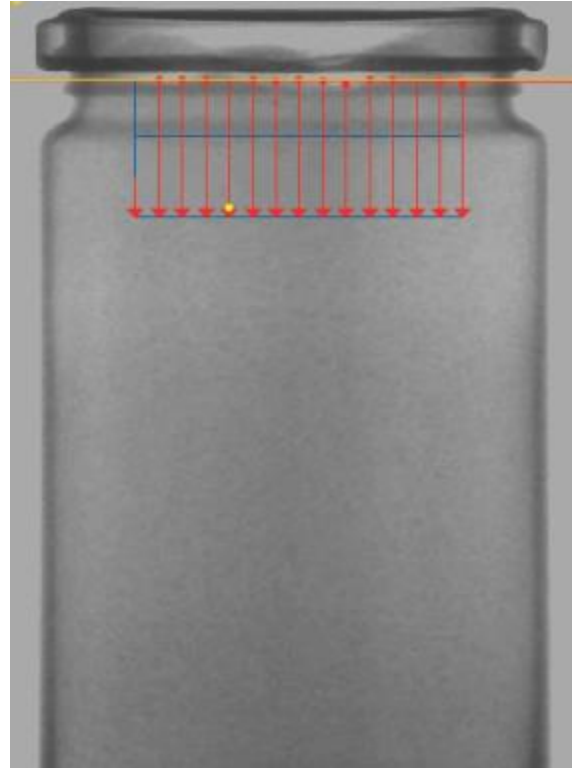
Video for sidewall module 2



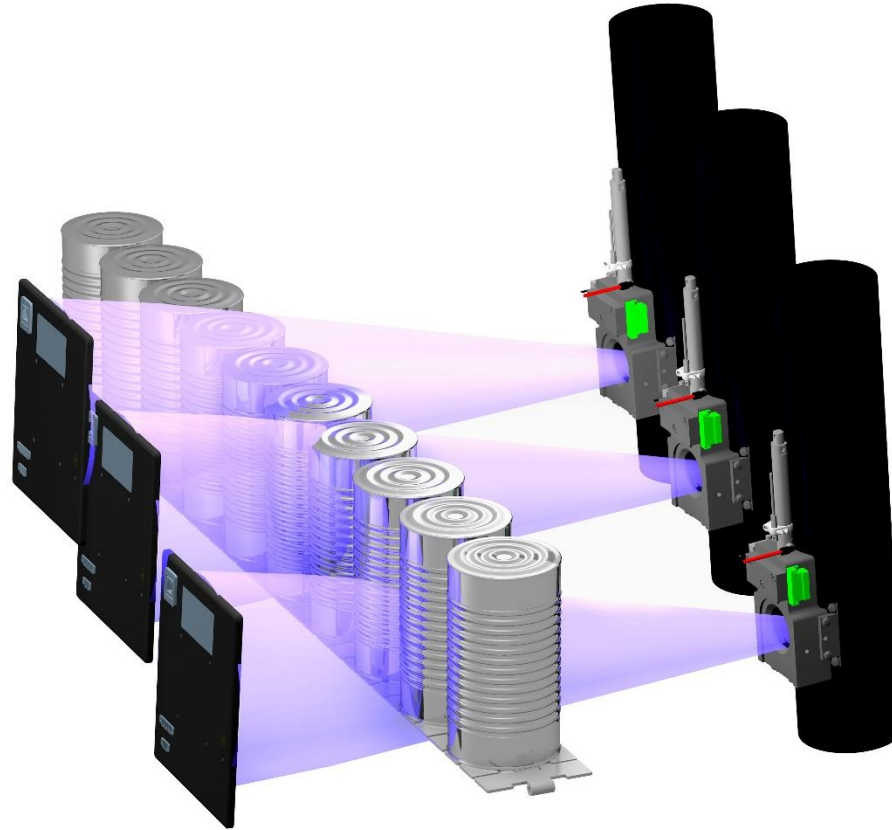
ENLIGHTENMENT



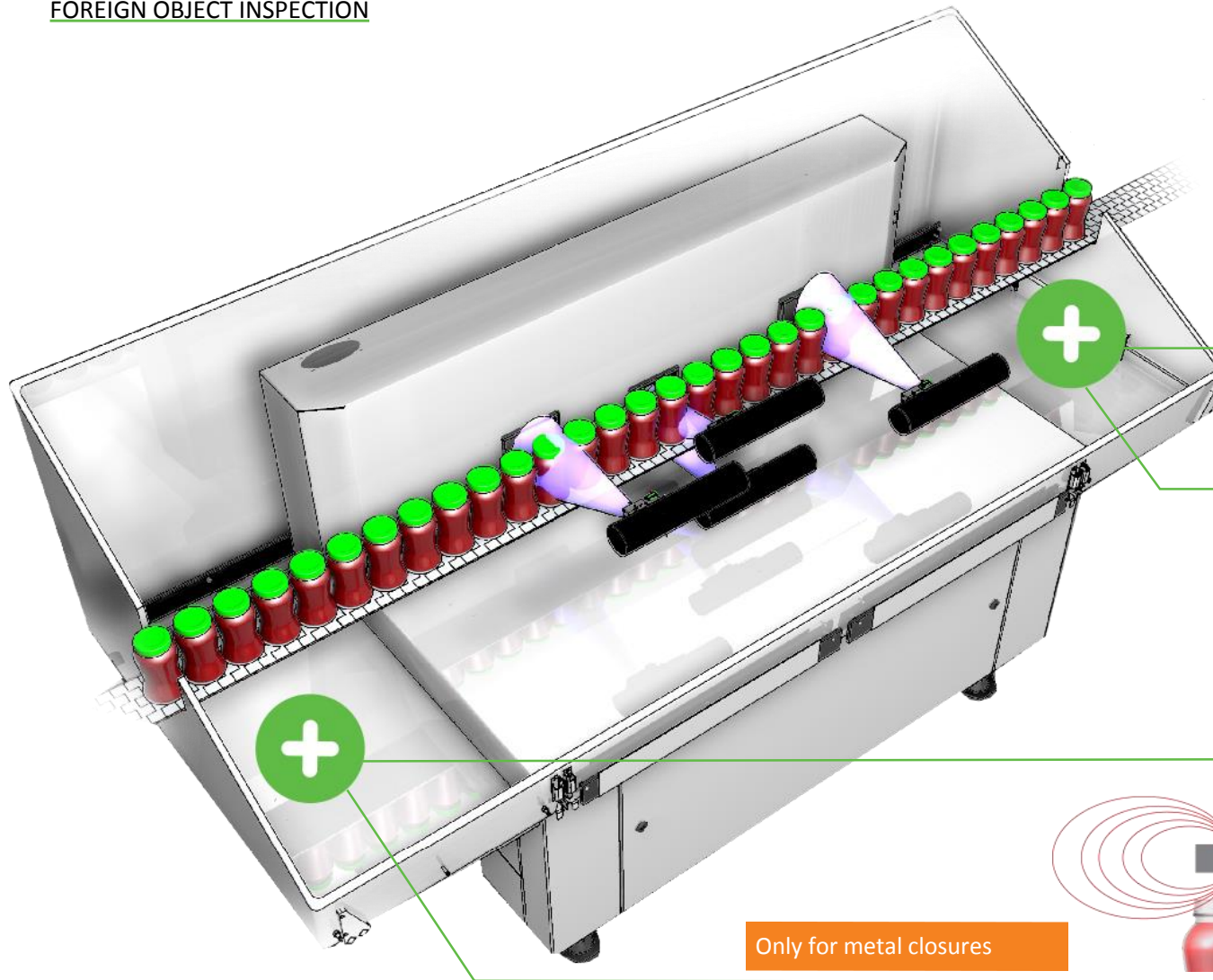
Enlightenment – sidewall modules



Fill level detection



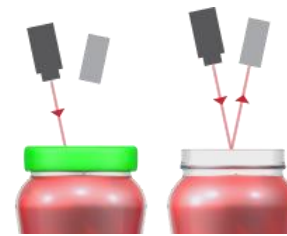
Equipment option for maximum inspection height



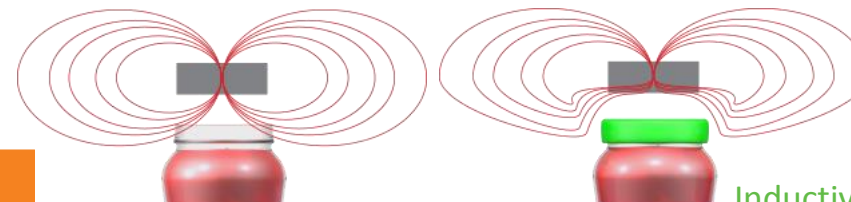
HEUFT *sonic*
Leakage check



Excessive height lid check



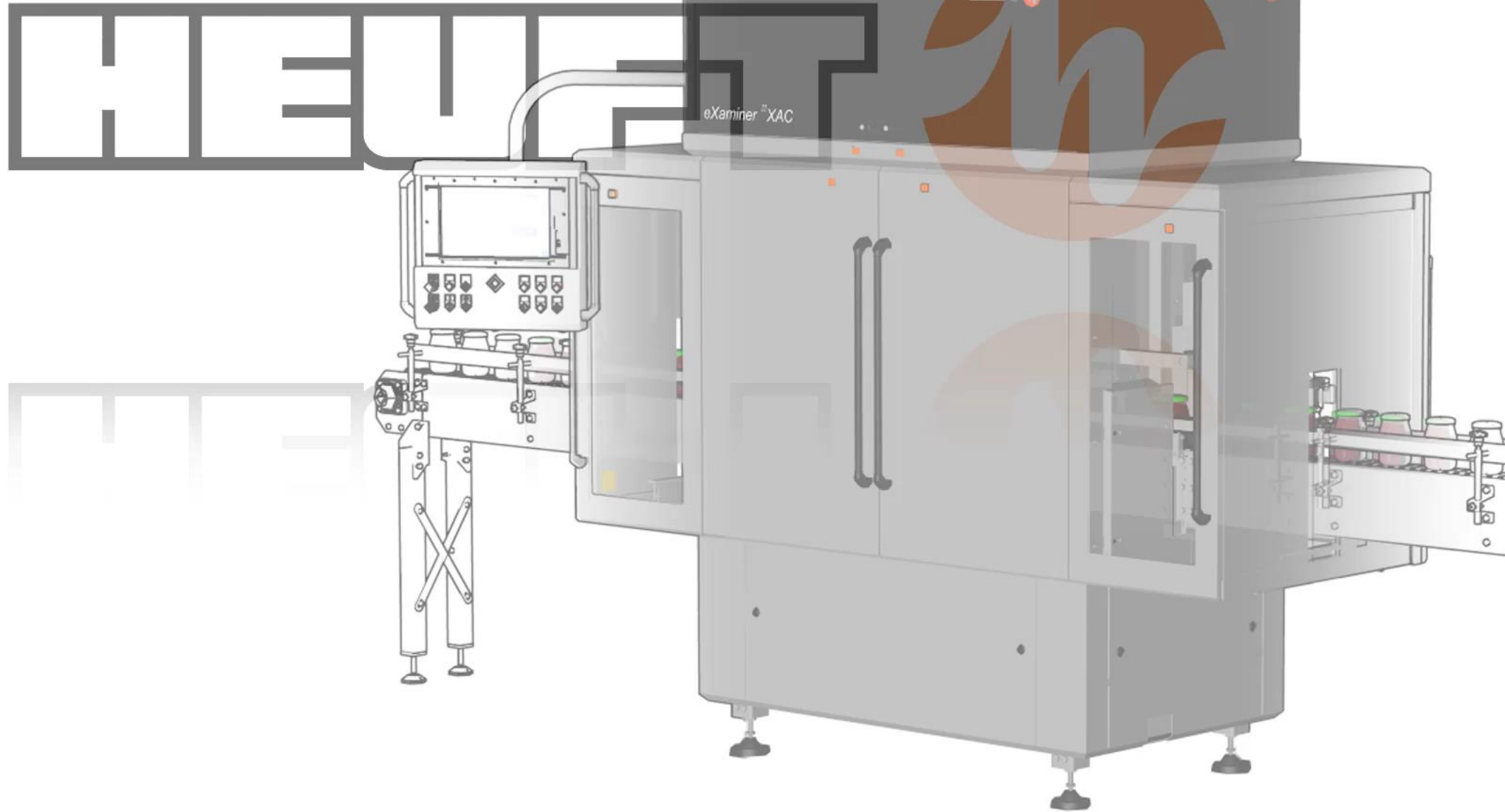
Optical closure presence



Inductive closure presence

Only for metal closures

HEUFT *eXaminer II* XAC: ADDITIONAL INSPECTION MODULES



Summary

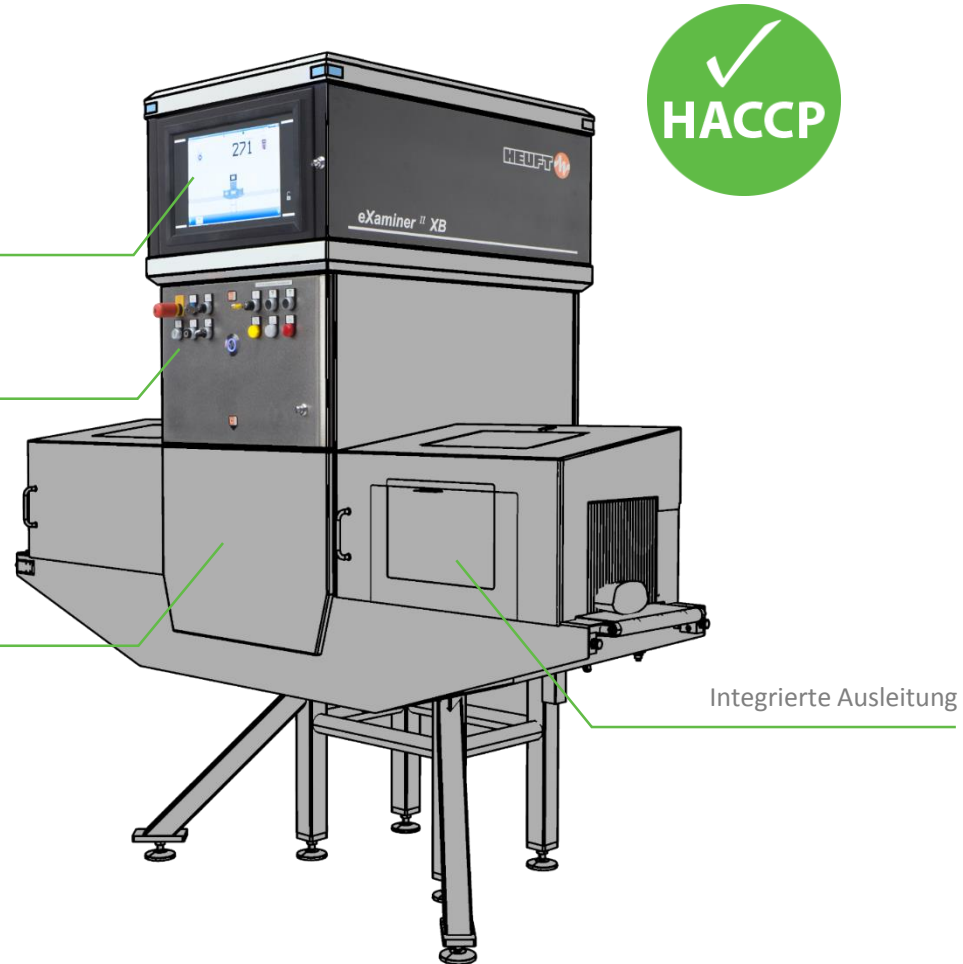
- Compact Turn-Key solution
- Everything from a single source
- Modular design
- Customer-specific integration solution
- Worldwide unique pulsed X-ray technology from HEUFT
- Real-time image processing system with high detection performance
- Manipulationssichere Fremdkörpererkennung
- Audiovisual user guidance



Top-down inspection with pulsed X-ray technology
based on the HEUFT *SPECTRUM II*.

HEUFT *eXaminer II* XB

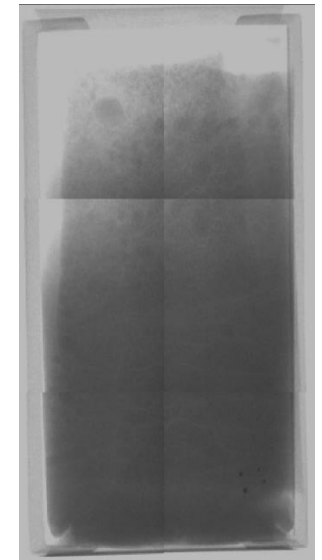
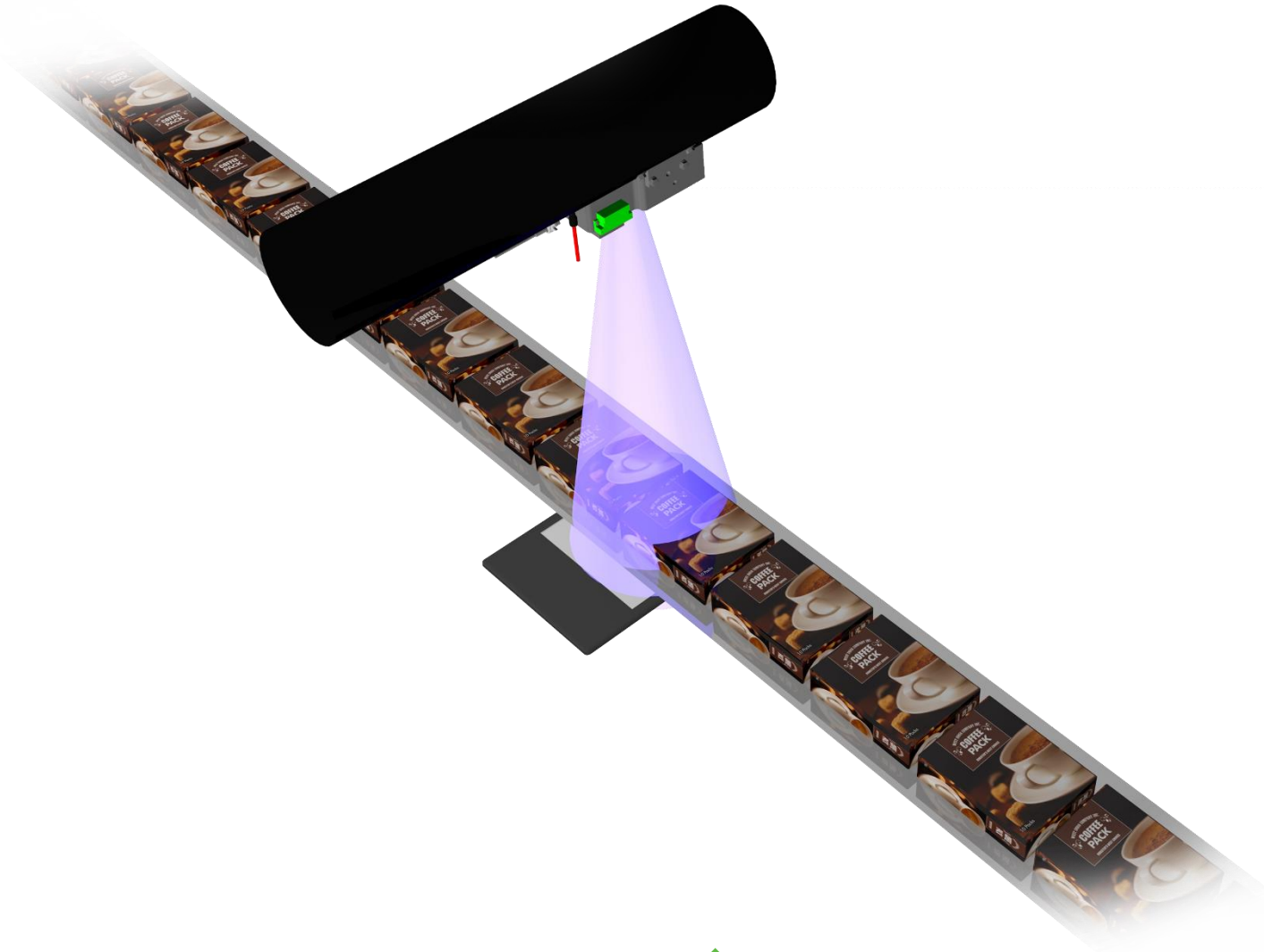




automatischer Sortenwechsel

Turnkey-Lösung

TOP-DOWN INSPECTION



HEUFT *eXaminer^{II}* XB: Top-Down-Inspektion einfach

TOP-DOWN INSPECTION



HEUFT *eXaminer II* XB: Weite einfache Top-Down-Inspektion

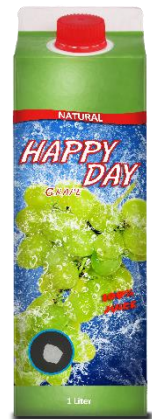
Summary

- Compact Turn-Key solution
- Everything from a single source
- Modular design
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- Manipulationssichere Fremdkörpererkennung
- Audiovisual user guidance



Space saving End-of-Line-X-ray inspection of the latest generation with full coverage of the sidewall.

HEUFT *eXaminer II XS*



FOREIGN OBJECT INSPECTION



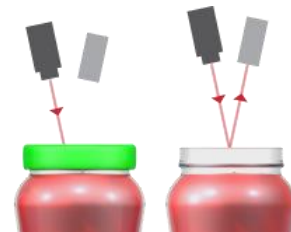
Additional inspection modules



HEUFT *sonic*
Leakage check



Excessive height
lid check



Optical closure presence



Check of lable presence

Operating unit

Inspection

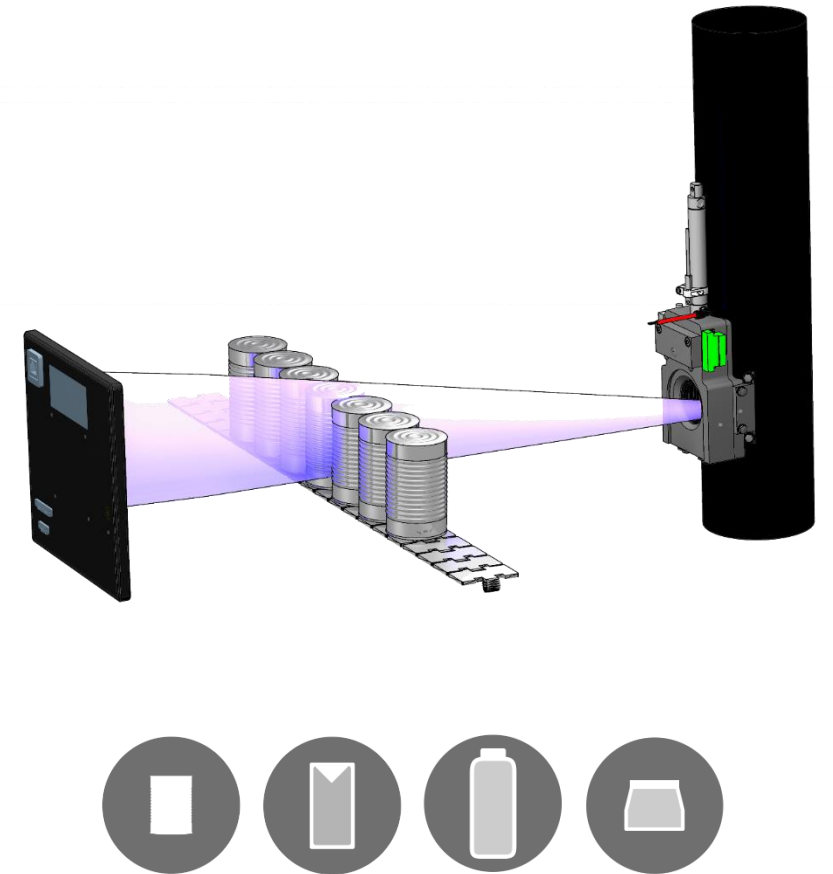
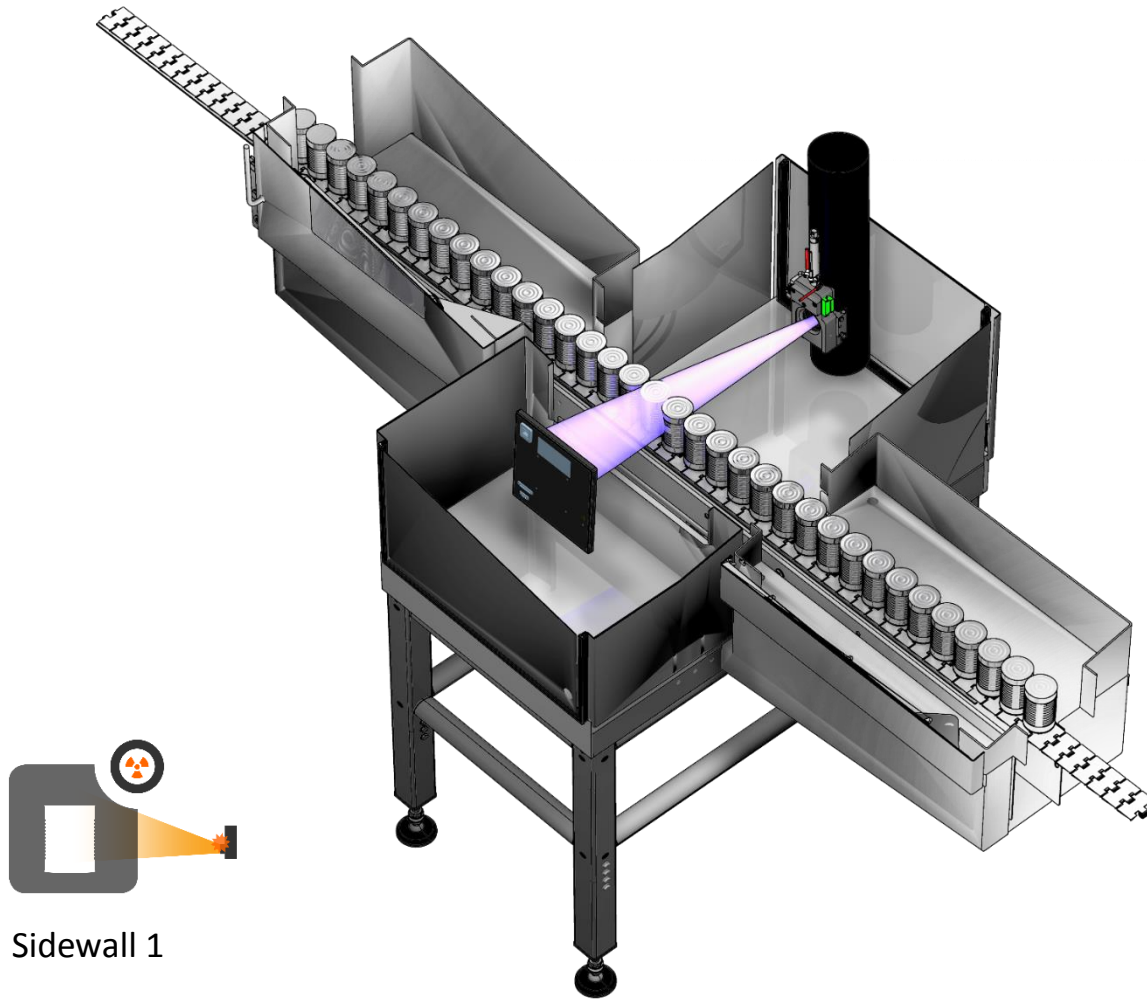
HACCP

MHI



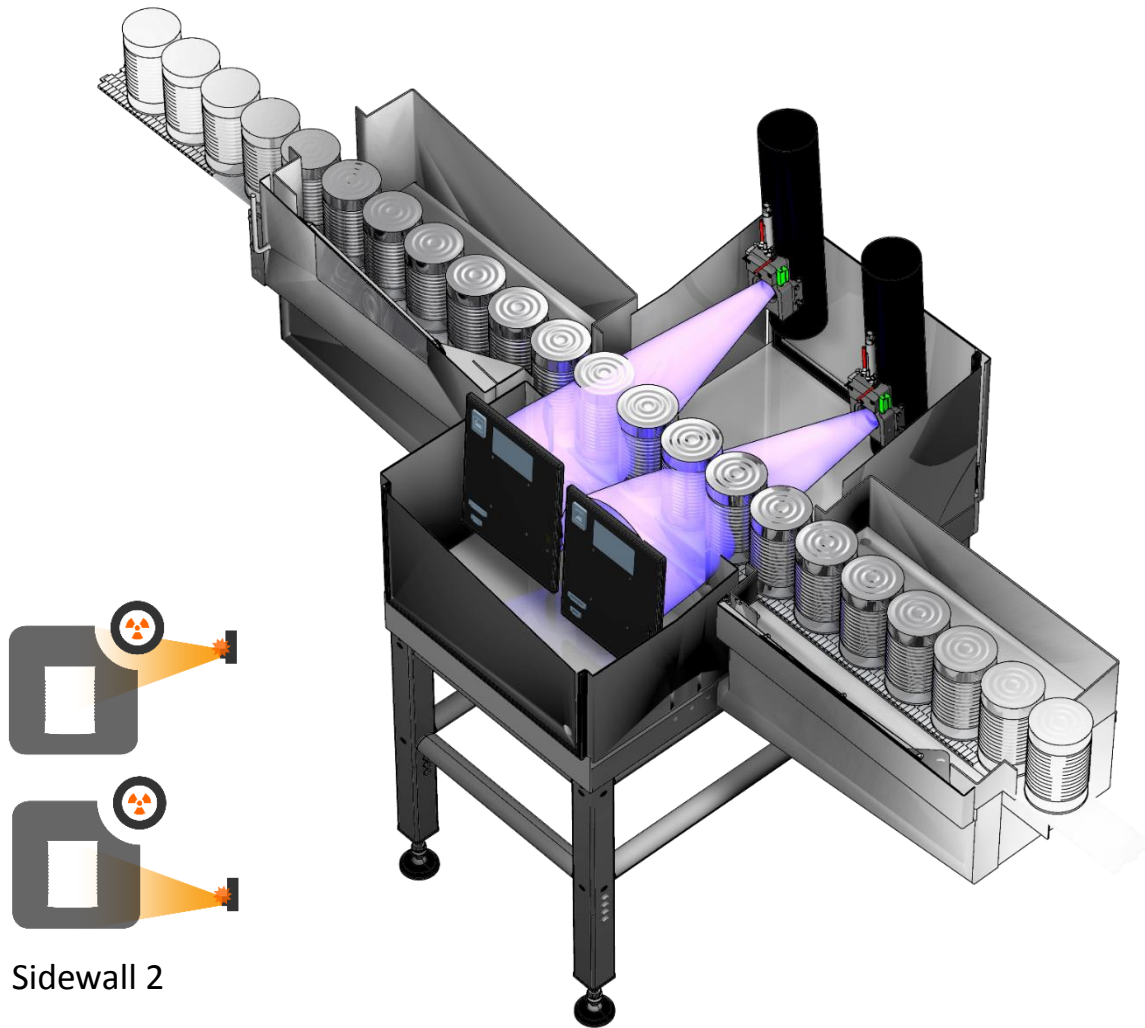
Automatic brand change

HEUFT *eXaminer II* XS: Space saving Turnkey-Lösung

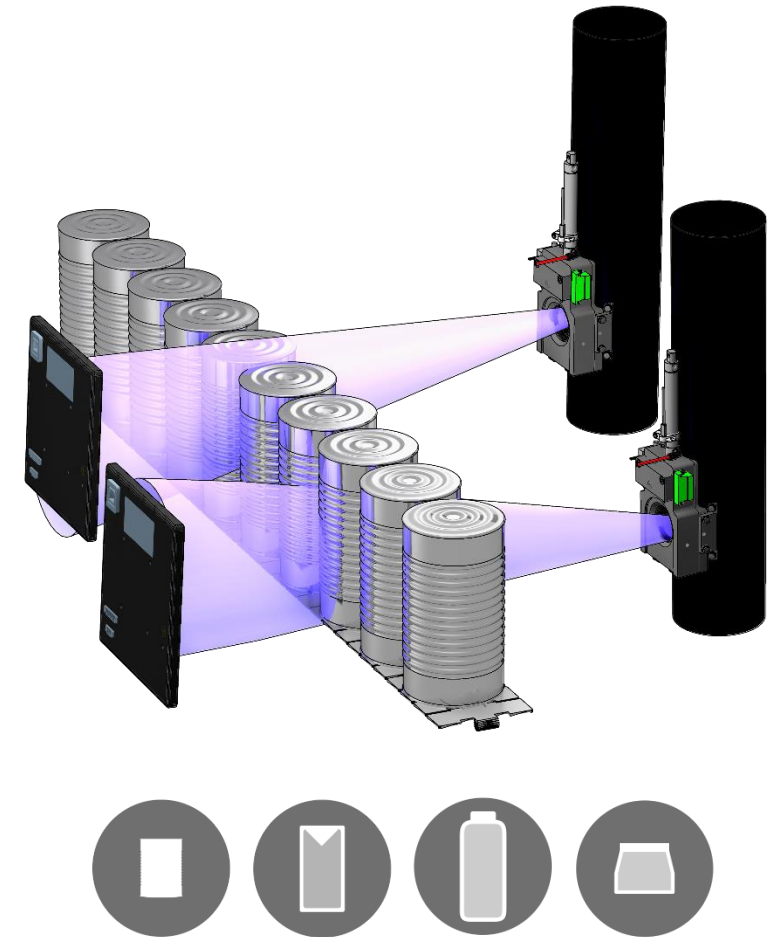


HEUFT *eXaminer II* XS: Single sidewall inspection

Sidewall inspection

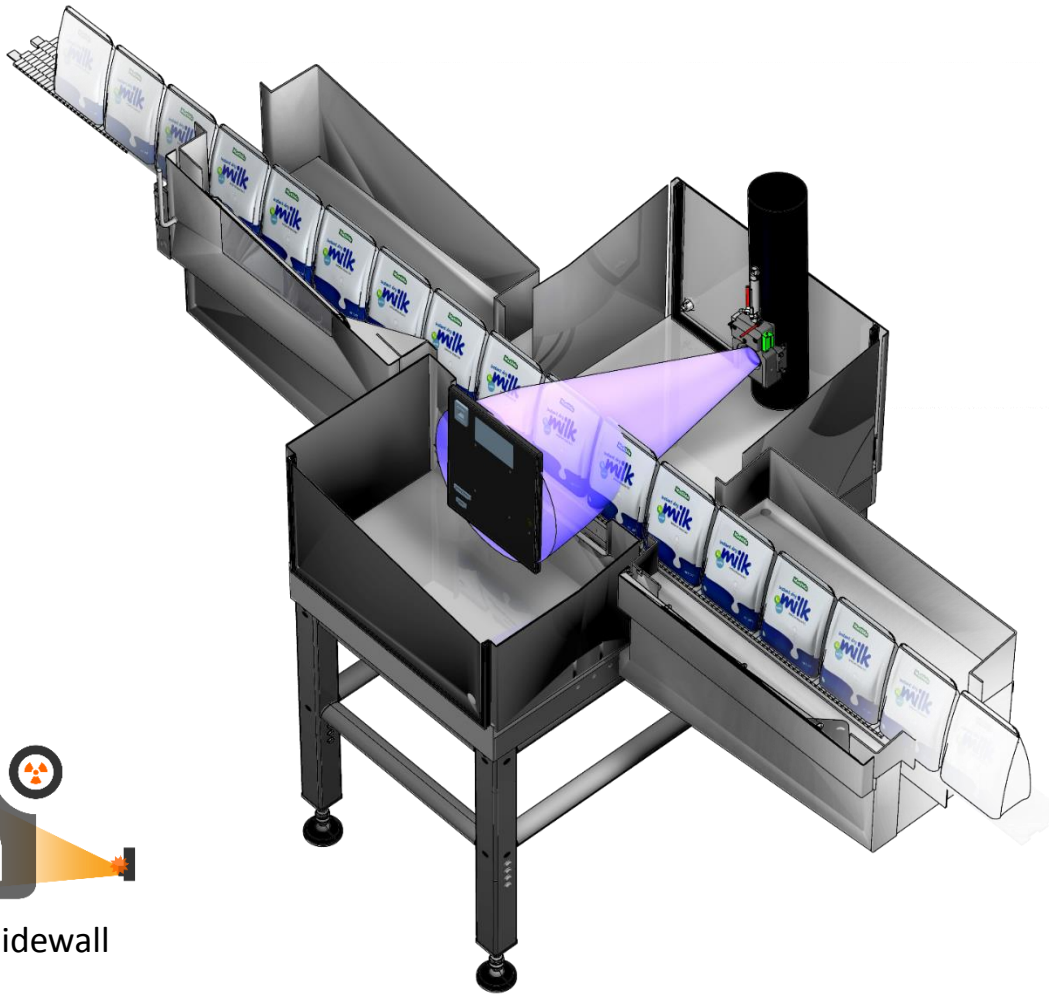


Sidewall 2

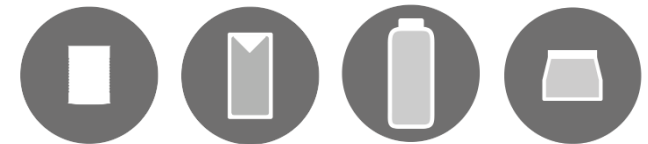
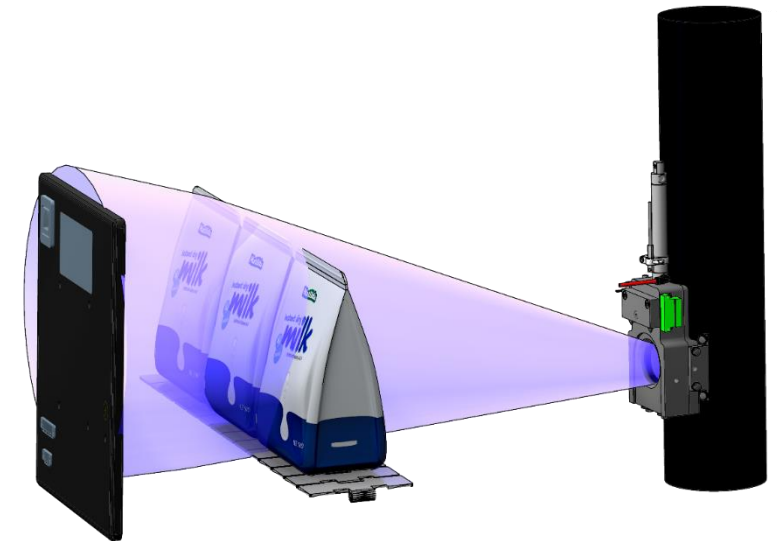


HEUFT *eXaminer II* XS: Double sidewall inspection

Sidewall inspection



Extended sidewall



HEUFT *eXaminer II* XS: Extended sidewall inspection

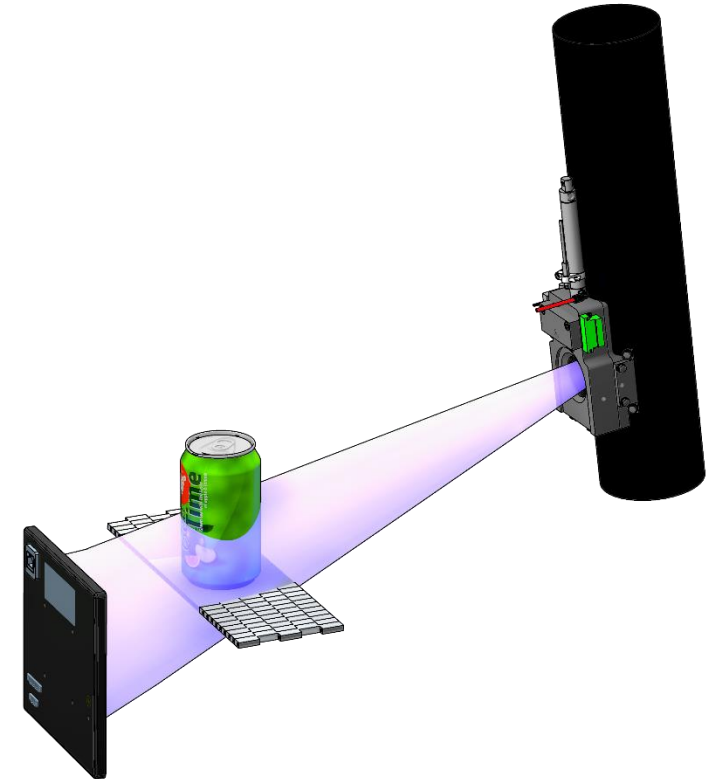
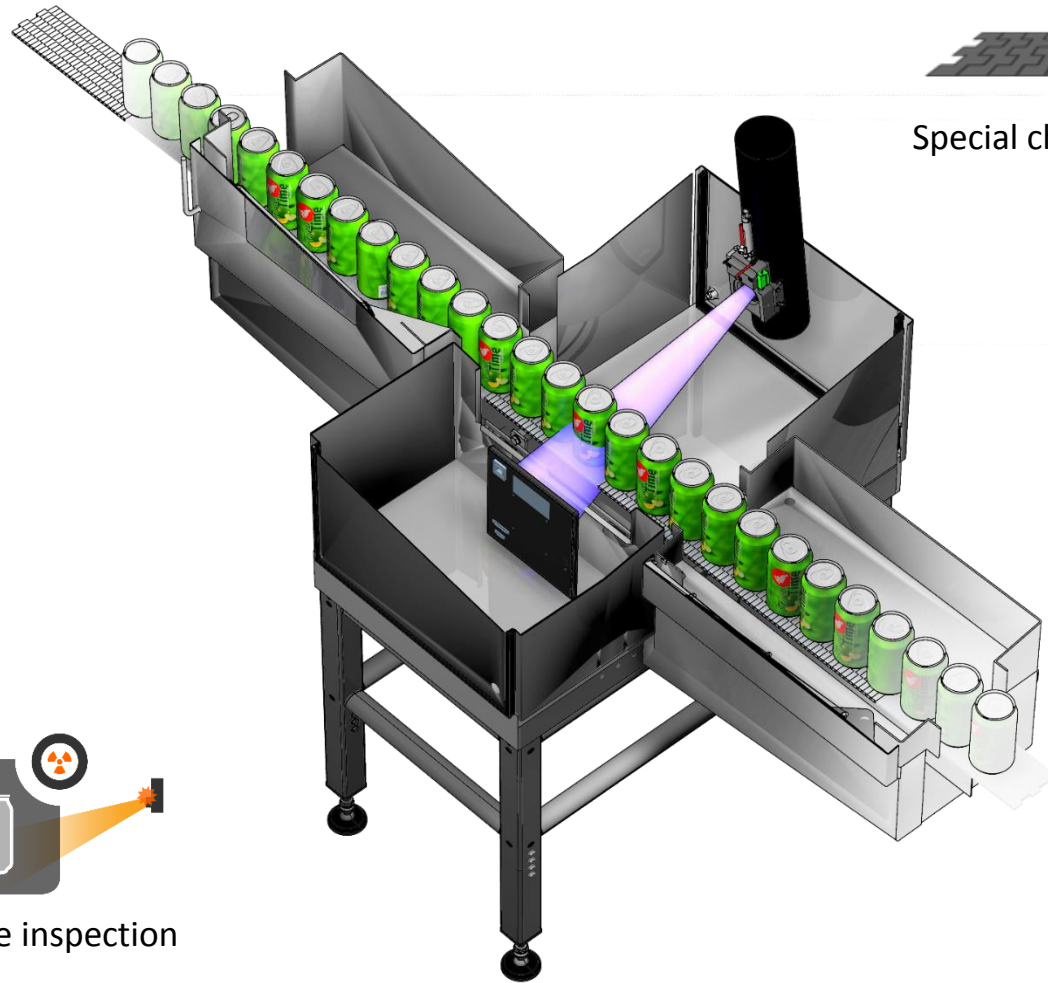
Base inspection



Special chain



Single base inspection



HEUFT *eXaminer II* XS: Single base inspection

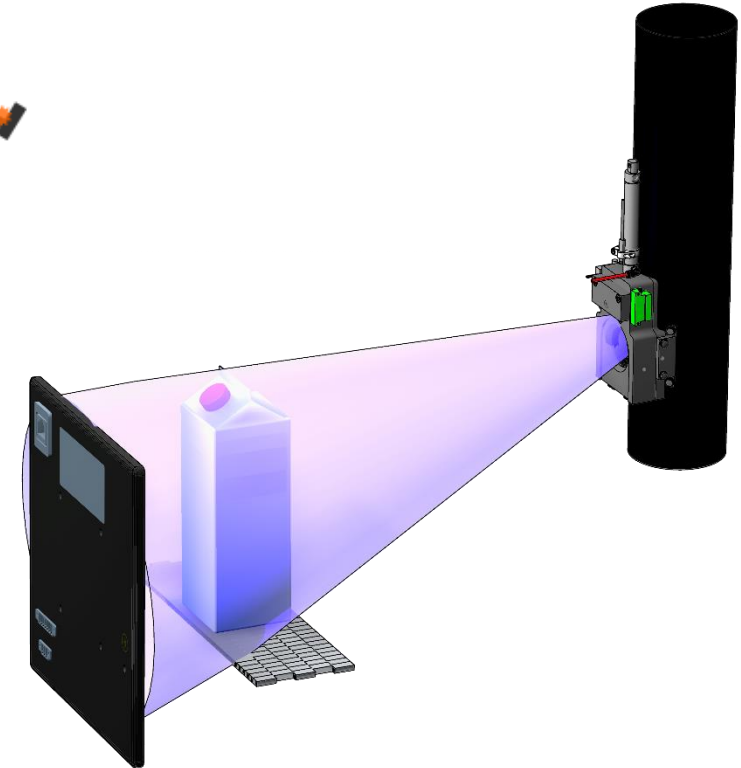
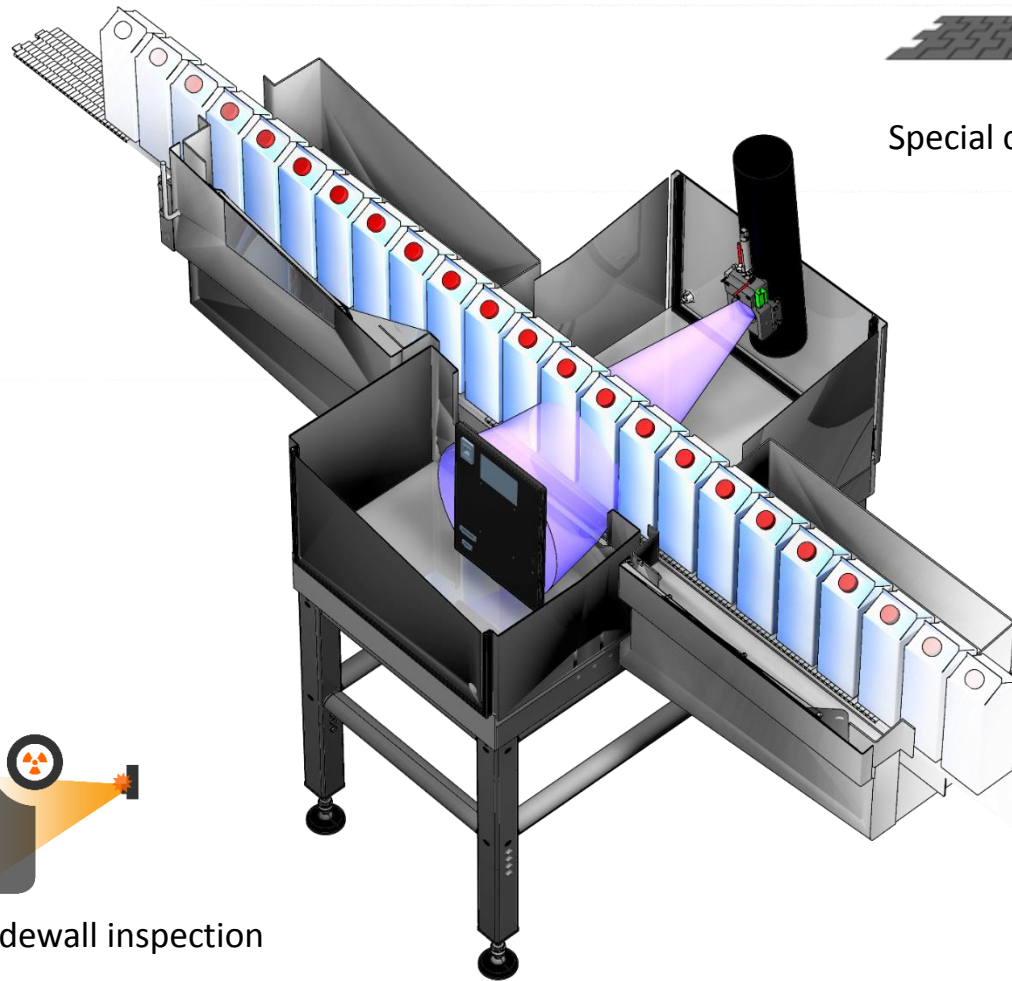
Base and sidewall inspection



Special chain



Base and sidewall inspection



HEUFT *eXaminer II* XS: Base and sidewall inspection

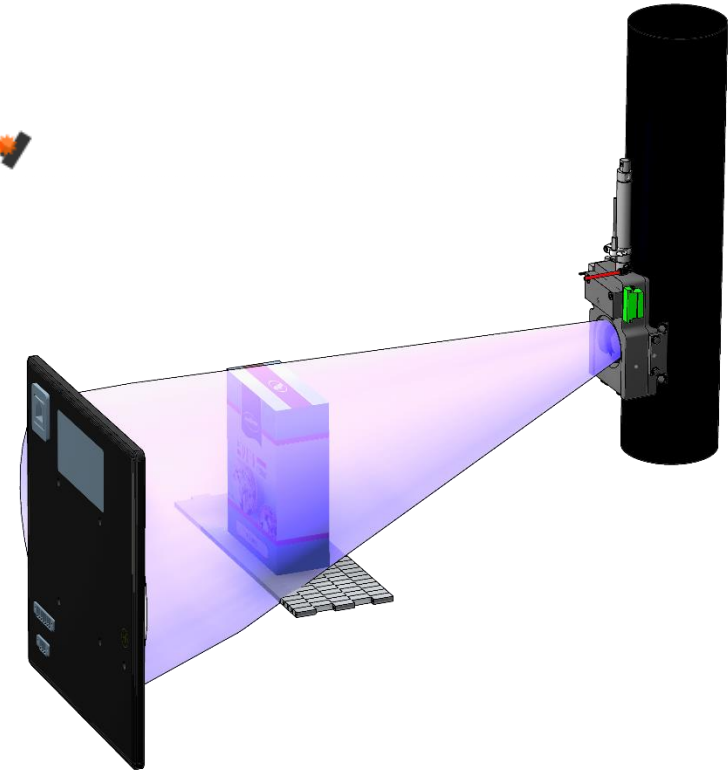
Base sidewall inspection



Special chain



Base and sidewall inspection



HEUFT *eXaminer^{II}* XS: Base and sidewall inspection

Summary

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